Radiation Report

UC1708-SP Neutron Displacement Damage (NDD) Characterization

ABSTRACT

This report presents the effect of neutron displacement damage (NDD) on the UC1708-SP device. The results show that all devices were fully functional and within production test limits after having been irradiated up to 5 × 10^{12} n/cm^2 (1-MeV equivalent). A sample size of nine units was exposed to radiation testing per MIL-STD-883 (Method 1017 for neutron irradiation) and an additional unirradiated sample device was used for correlation. Electrical testing was performed at Texas Instruments before and after neutron irradiation using the production test program for UC1708-SP.

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Trademarks

1 Overview

The UC1708 family of power drivers is made with a high-speed, high-voltage, Schottky process to interface control functions and high-power switching devices, particularly power MOSFETs. Operating over a 5-V to 35-V supply range, these devices contain two independent outputs. The A and B inputs are compatible with TTL and CMOS logic families, but can withstand input voltages as high as VIN. Each output can source or sink up to 3 A as long as power dissipation limits are not exceeded.

General device information and testing conditions are listed in Table 1-1.

Table 1-1. Overview Information

TI Part Number	**UC1708-SP**
Orderable Number	5962-0051401V2A
Device Function	Dual non-inverting power driver
Die Name	SMFZRC1708VTS
Package	20-pin FK (LCCC)
Technology	JI-PWR1
A/T Lot Number / Date Code	9006249 / 1928A
Unbiased Quantity Tested	9 + 2 control
Exposure Facility	VPT Radiation Laboratory and Test Services
Neutron Fluence (1-MeV equivalent)	1.0×10^{12}, 5.0×10^{12}, 1.0×10^{13} n/cm^2
Irradiation Temperature	25°C
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2 Test Procedures

The UC1708-SP was electrically pre-tested using the production automated test equipment (ATE) program.

General test procedures were IAW MIL-STD-883, Method 1017 for neutron irradiation of UC1708-SP.

Table 2-1. Neutron Irradiation Conditions

GROUP	SAMPLE QTY	NEUTRON FLUENCE (n/cm^2)	BIAS
A	3	1.0×10^{12}	Unbiased
B	3	5.0×10^{12}	Unbiased
C	3	1.0×10^{13}	Unbiased

Figure 2-1. UC1708-SP Device

TheUC1708-SP is packaged in a 20-pin thermally-enhanced dual ceramic flat pack package (LCCC) as shown in Figure 2-1.

3 Facility

VPT Rad performs all neutron displacement damage irradiations in a low-enriched, open-pool, water moderated, thermal neutron reactor. It utilizes flat-plate type fuel and has a maximum thermal energy output of up to 1 MW. The Fast Neutron Irradiator (FNI) faces one side of the reactor core. The FNI design produces a geometrical planar *beam* of fast neutrons that is approximately uniform over an area of 12 in × 20 in. Lead and thermal neutron absorbing compounds are combined to filter out both fission gammas and thermal neutrons. The ratio of fast-to-thermal neutrons is approximately 400:1, with a gamma exposure of up to 1401 rad(Si) for a 1E13 n/cm^2 (1-MeV(Si) equivalent) exposure. The FNI can accommodate a sample or samples with size up to 30 cm in diameter and 15-cm thick including packaging materials. The minimum neutron fluence rate is 1E6 n/cm^2-s. The maximum neutron fluence rate is approximately 1.0E11 n/cm^2-s (both values are 1-MeV(Si) equivalent).

The neutron fluence rate is determined using the previously-measured neutron radiation field for the FNI, performed in accordance with ASTM standards (ASTM F1190), and correlated to the measured reactor power level. The neutron dose is timed to meet the customer-specified fluence for the irradiation. Neutron dosimetry meeting ASTM standards (ASTM E265) is utilized to track and ensure irradiations meet the required minimum. The facility retains *source-suitability* with the Defense Logistics Agency (DLA) Laboratory Suitability Program for ASTM Test Method 1017. The DUTS are typically irradiation in an unbiased condition as per TM1017. If bias conditions are required, they can be maintained via dry thimbles connected to the irradiation volume.

4 Results

There were no functional failures at any irradiation level up to 5.0 × 10^{12} n/cm^2. All parametric measurements remained well within all data sheet (SLUS171) limits up to 5.0 × 10^{12} n/cm^2. All parametric measurements remained well within the production test limits which are guard-banded from the data sheet limits up to 5.0 × 10^{12} n/cm^2. The full parameter list and graphs are found in Appendix A.

Table 4-1 lists the UC1708-SP specification compliance matrix.

Table 4-1. UC1708-SP Specification Compliance Matrix

PARAMETER	TEST CONDITION	UC1708-SP DATA SHEET (SLUS171)			ATE TEST #
		MIN	MAX	UNIT	
V_{IN} supply current	Outputs low		26	mA	2,3
	Outputs high		18		4,5
V_{IN} – V_{OUT} output high saturation	I_{OUT} = –50 mA		2.0	V	8,10,80,20,83,22
	I_{OUT} = –500 mA		2.5		9,11,21,23
V_{OUT} output low saturation	I_{OUT} = 50 mA		0.5	V	12,81,14,16,18,82
	I_{OUT} = 500 mA		2.5		13,15,17,19
A, B input current low	$V_{A,B}$ = 0.4 V	–1		mA	24,25,34,35
A, B input current high	$V_{A,B}$ = 2.4 V	–200	50	µA	26,27,30,31
A, B input current leakage high	$V_{A,B}$ = 35.3 V		200	µA	28,32
Shutdown input current Low	$V_{SHUTDOWN}$ = 0.4 V		100	µA	36,37
Shutdown input current high	$V_{SHUTDOWN}$ = 2.4 V		500	µA	38,39
	$V_{SHUTDOWN}$ = 6.2 V		1.5	mA	40,41
Enable input current low	V_{ENABLE} = 0 V	–600	200	µA	42,43
Enable input current high	V_{ENABLE} = 6.2 V		200	µA	44,45
Enable threshold rising			3.6	V	46,49
Enable threshold falling		1.0	3.4	V	47,48
From A, B Input to Output					
Rise time delay (TPLH)	CL = 0 pF		40	ns	50,58
	CL = 1000 pF		45		
	CL = 2200 pF		50		51,59
Fall time delay (TPHL)	CL = 0 pF		45	ns	53,61
	CL = 1000 pF		50		
	CL = 2200 pF		55		52,60
10% to 90% rise (TTLH)	CL = 0 pF		75	ns	54,62
	CL = 1000 pF		80		
	CL = 2200 pF		85		55,63
90% to 10% fall (TTHL)	CL = 0 pF		20	ns	57,65
	CL = 1000 pF		45		
	CL = 2200 pF		55		56,64
From Shutdown Input to Output					
Rise time delay (TPLH)	CL = 0 pF		75	ns	66,70
	CL = 1000 pF		80		
	CL = 2200 pF		85		67,71
Fall time delay (TPHL)	CL = 0 pF		45	ns	69,73
	CL = 1000 pF		50		
	CL = 2200 pF		55		68,72

Table 4-1. UC1708-SP Specification Compliance Matrix (continued)

PARAMETER	TEST CONDITION	UC1708-SP DATA SHEET (SLUS171)			ATE TEST #
		MIN	MAX	UNIT	
Total supply current	F = 200 kHz, 50% duty cycle, both channels; CL = 0 pF		25	mA	74
	F = 200 kHz, 50% duty cycle, both channels; CL = 2200 pF		45		75

A Appendix: NDD Test Results

This appendix contains the detailed NDD test results.

NDD Report
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NDD Report
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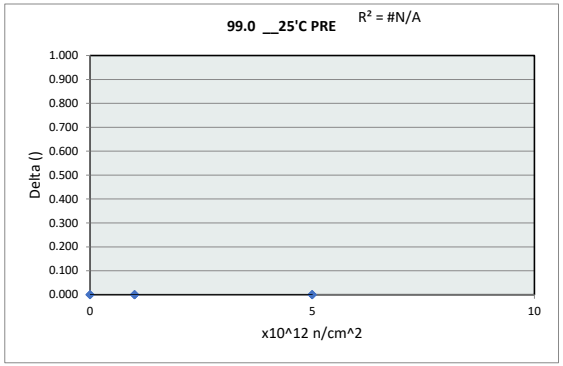
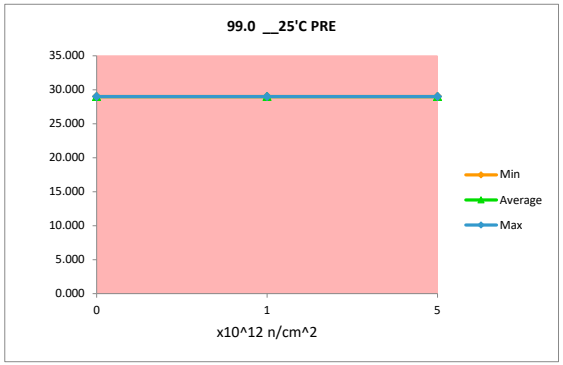
		99.0 __25'C PRE	
Test Site		MTT	MTT
Tester		LTX	LTX
Test Number		XPM02903	XPM02903
Unit			
Max Limit			
Min Limit			
x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	29.000	29.000	0.000
1	113	29.000	29.000	0.000
1	114	29.000	29.000	0.000
5	115	29.000	29.000	0.000
5	118	29.000	29.000	0.000
5	119	29.000	29.000	0.000
0	123	29.000	29.000	0.000
0	124	29.000	29.000	0.000
	Max	29.000	29.000	0.000
	Average	29.000	29.000	0.000
	Min	29.000	29.000	0.000
	Std Dev	0.000	0.000	0.000



	99.0 __25'C PRE		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit			
Min Limit			
x10^12 n/cm^2	0	1	5
LL			
Min	29.000	29.000	29.000
Average	29.000	29.000	29.000
Max	29.000	29.000	29.000
UL			



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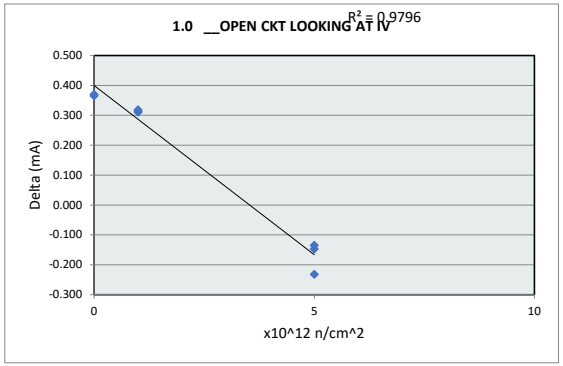
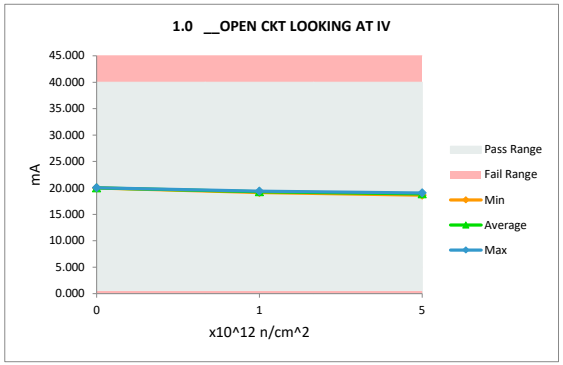
	1.0 __OPEN CKT LOOKING AT IV	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	40	40
Min Limit	0.5	0.5

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	18.973	19.292	0.318
1	113	18.835	19.147	0.312
1	114	19.077	19.387	0.311
5	115	19.074	18.939	-0.135
5	118	18.860	18.628	-0.232
5	119	19.188	19.040	-0.148
0	123	19.621	19.991	0.370
0	124	19.659	20.025	0.365
	Max	19.659	20.025	0.370
	Average	19.161	19.306	0.145
	Min	18.835	18.628	-0.232
	Std Dev	0.318	0.490	0.265



	1.0 __OPEN CKT LOOKING AT		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	40	mA	
Min Limit	0.5	mA	
x10^12 n/cm^2	0	1	5
LL	0.500	0.500	0.500
Min	19.991	19.147	18.628
Average	20.008	19.275	18.869
Max	20.025	19.387	19.040
UL	40.000	40.000	40.000



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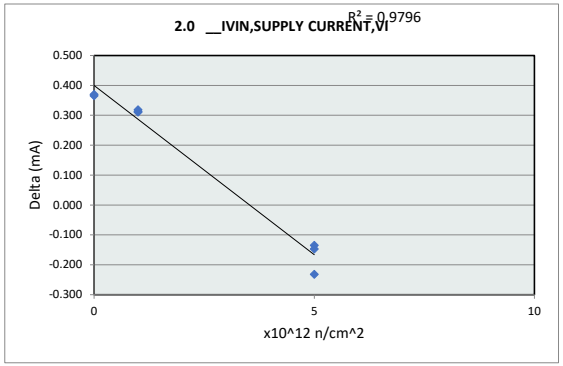
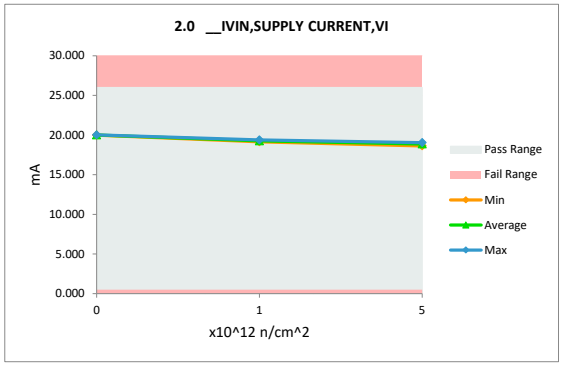
	2.0 __IVIN,SUPPLY CURRENT,VI	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	26	26
Min Limit	0.5	0.5

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	18.973	19.292	0.318
1	113	18.835	19.147	0.312
1	114	19.077	19.387	0.311
5	115	19.074	18.939	-0.135
5	118	18.860	18.628	-0.232
5	119	19.188	19.040	-0.148
0	123	19.621	19.991	0.370
0	124	19.659	20.025	0.365
	Max	19.659	20.025	0.370
	Average	19.161	19.306	0.145
	Min	18.835	18.628	-0.232
	Std Dev	0.318	0.490	0.265



	2.0 __IVIN,SUPPLY CURRENT,		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	26	mA	
Min Limit	0.5	mA	
x10^12 n/cm^2	0	1	5
LL	0.500	0.500	0.500
Min	19.991	19.147	18.628
Average	20.008	19.275	18.869
Max	20.025	19.387	19.040
UL	26.000	26.000	26.000



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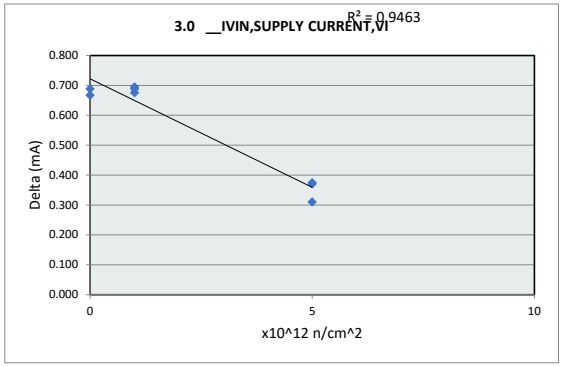
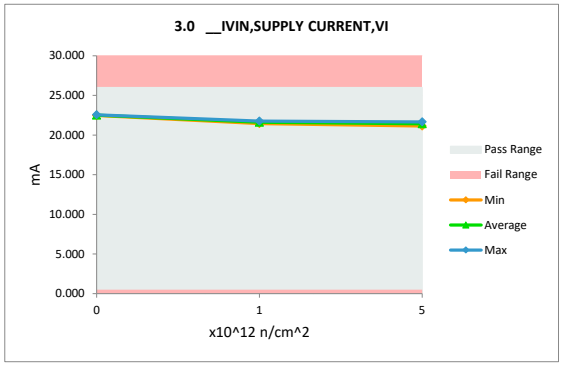
	3.0 __IVIN,SUPPLY CURRENT,VI	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	26	26
Min Limit	0.5	0.5

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	20.971	21.659	0.688
1	113	20.749	21.444	0.695
1	114	21.078	21.753	0.676
5	115	21.162	21.471	0.310
5	118	20.773	21.144	0.371
5	119	21.282	21.656	0.374
0	123	21.808	22.475	0.667
0	124	21.864	22.552	0.689
	Max	21.864	22.552	0.695
	Average	21.211	21.769	0.559
	Min	20.749	21.144	0.310
	Std Dev	0.426	0.496	0.173



	3.0 __IVIN,SUPPLY CURRENT,		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	26	mA	
Min Limit	0.5	mA	
x10^12 n/cm^2	0	1	5
LL	0.500	0.500	0.500
Min	22.475	21.444	21.144
Average	22.514	21.619	21.424
Max	22.552	21.754	21.656
UL	26.000	26.000	26.000



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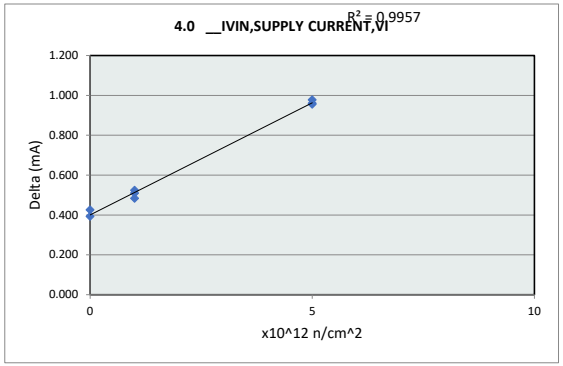
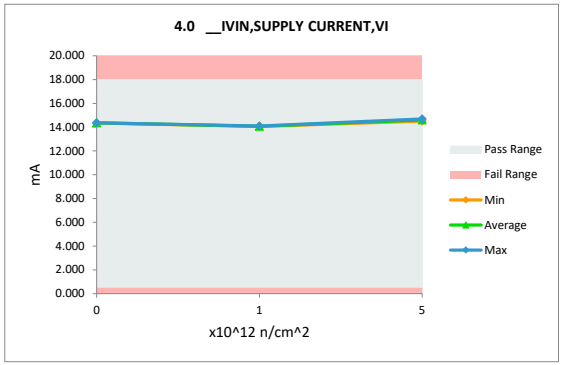
	4.0 __IVIN,SUPPLY CURRENT,VI	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	18	18
Min Limit	0.5	0.5

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	13.538	14.062	0.524
1	113	13.586	14.095	0.509
1	114	13.575	14.058	0.483
5	115	13.661	14.621	0.960
5	118	13.533	14.510	0.978
5	119	13.733	14.689	0.956
0	123	13.976	14.369	0.393
0	124	13.915	14.341	0.426
	Max	13.976	14.689	0.978
	Average	13.690	14.343	0.653
	Min	13.533	14.058	0.393
	Std Dev	0.172	0.253	0.261



	4.0 __IVIN,SUPPLY CURRENT,		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	18	mA	
Min Limit	0.5	mA	
x10^12 n/cm^2	0	1	5
LL	0.500	0.500	0.500
Min	14.341	14.058	14.510
Average	14.355	14.072	14.606
Max	14.369	14.096	14.689
UL	18.000	18.000	18.000



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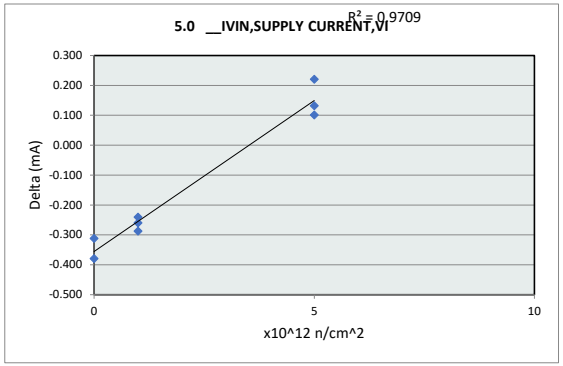
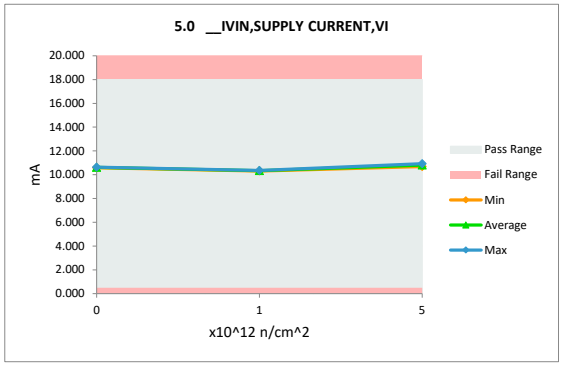
	5.0 __IVIN,SUPPLY CURRENT,VI	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	18	18
Min Limit	0.5	0.5

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	10.568	10.308	-0.260
1	113	10.635	10.348	-0.287
1	114	10.599	10.358	-0.241
5	115	10.674	10.806	0.132
5	118	10.585	10.686	0.101
5	119	10.707	10.927	0.220
0	123	11.009	10.630	-0.379
0	124	10.903	10.591	-0.312
	Max	11.009	10.927	0.220
	Average	10.710	10.582	-0.128
	Min	10.568	10.308	-0.379
	Std Dev	0.161	0.228	0.237



	5.0 __IVIN,SUPPLY CURRENT,		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	18	mA	
Min Limit	0.5	mA	
x10^12 n/cm^2	0	1	5
LL	0.500	0.500	0.500
Min	10.591	10.308	10.686
Average	10.610	10.338	10.806
Max	10.630	10.358	10.927
UL	18.000	18.000	18.000



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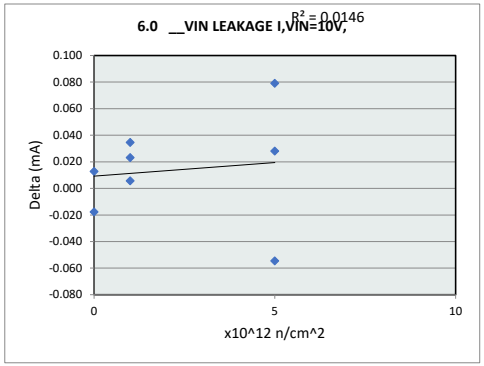
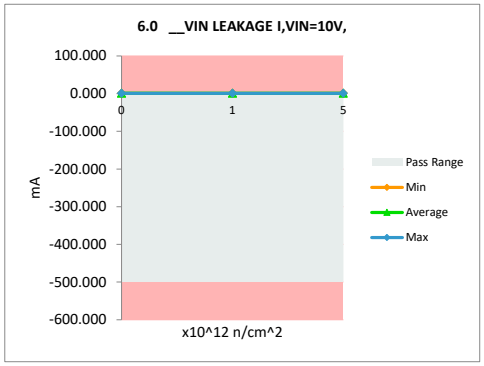
	6.0 __VIN LEAKAGE I,VIN=10V,	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	3.6	3.6
Min Limit	-500	-500

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.803	0.826	0.023
1	113	0.753	0.788	0.035
1	114	0.805	0.811	0.006
5	115	0.817	0.845	0.028
5	118	0.736	0.815	0.079
5	119	0.881	0.826	-0.055
0	123	0.808	0.821	0.013
0	124	0.844	0.826	-0.018
	Max	0.881	0.845	0.079
	Average	0.806	0.820	0.014
	Min	0.736	0.788	-0.055
	Std Dev	0.046	0.017	0.039



	6.0 __VIN LEAKAGE I,VIN=10		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	3.6	mA	
Min Limit	-500	mA	
x10^12 n/cm^2	0	1	5
LL	-500.000	-500.000	-500.000
Min	0.821	0.788	0.815
Average	0.824	0.808	0.829
Max	0.826	0.826	0.846
UL	3.600	3.600	3.600



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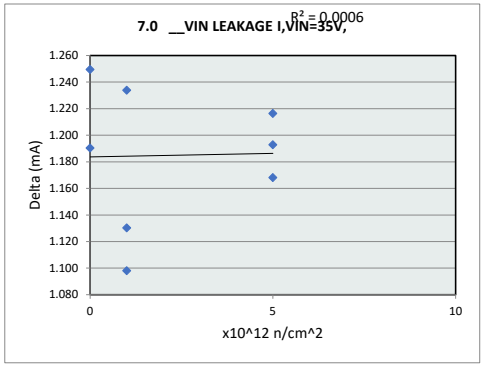
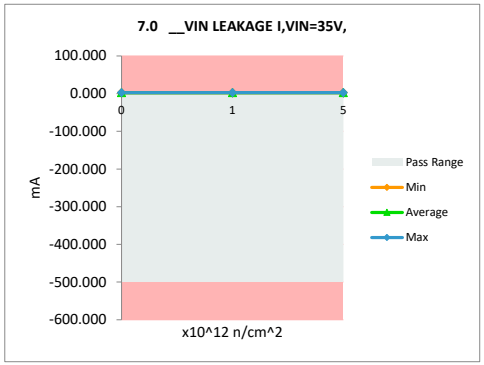
	7.0 __VIN LEAKAGE I,VIN=35V,	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	3.6	3.6
Min Limit	-500	-500

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.483	2.717	1.234
1	113	1.434	2.533	1.098
1	114	1.596	2.726	1.130
5	115	1.553	2.721	1.168
5	118	1.498	2.715	1.216
5	119	1.545	2.738	1.193
0	123	1.469	2.659	1.190
0	124	1.478	2.727	1.249
	Max	1.596	2.738	1.249
	Average	1.507	2.692	1.185
	Min	1.434	2.533	1.098
	Std Dev	0.053	0.069	0.051

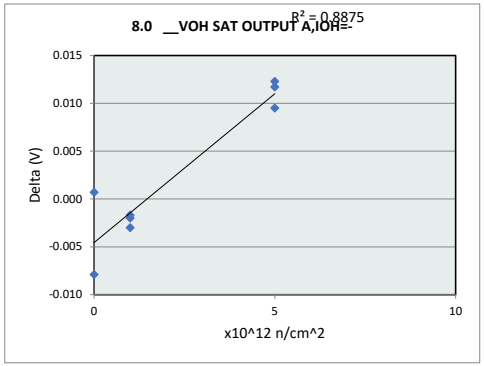


	7.0 __VIN LEAKAGE I,VIN=35		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	3.6	mA	
Min Limit	-500	mA	
x10^12 n/cm^2	0	1	5
LL	-500.000	-500.000	-500.000
Min	2.659	2.533	2.715
Average	2.693	2.659	2.725
Max	2.727	2.726	2.738
UL	3.600	3.600	3.600

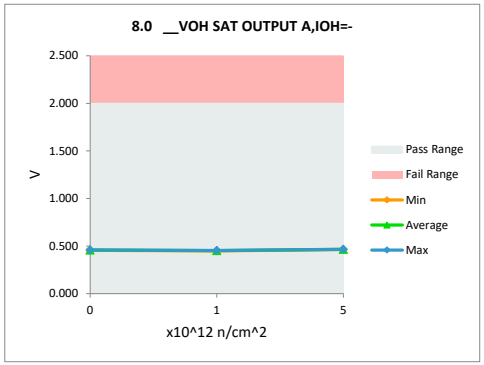


NDD Report
UC1708-SP

	8.0 __VOH SAT OUTPUT A,IOH=		
Test Site	MTT	MTT	
Tester	LTX	LTX	
Test Number	XPM02903	XPM02903	
Unit	V	V	
Max Limit	2	2	
Min Limit	0	0	
x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.452	0.449	-0.003
1	113	0.456	0.454	-0.002
1	114	0.454	0.453	-0.002
5	115	0.454	0.466	0.012
5	118	0.457	0.466	0.009
5	119	0.451	0.464	0.012
0	123	0.458	0.458	0.001
0	124	0.464	0.456	-0.008
	Max	0.464	0.466	0.012
	Average	0.456	0.458	0.002
	Min	0.451	0.449	-0.008
	Std Dev	0.004	0.006	0.008



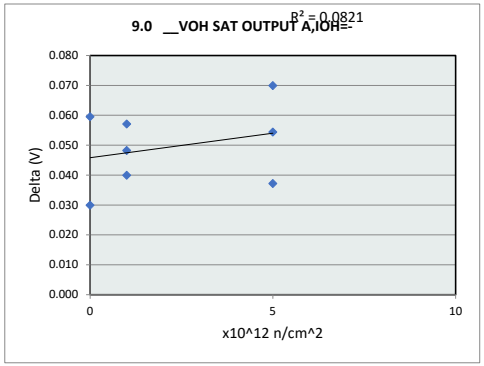
	8.0 __VOH SAT OUTPUT A,IOH		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	0.456	0.449	0.464
Average	0.457	0.452	0.465
Max	0.459	0.454	0.466
UL	2.000	2.000	2.000



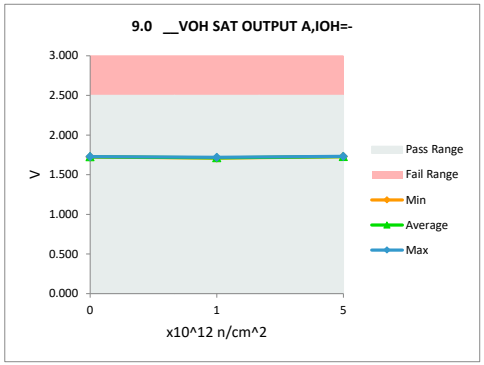
NDD Report
UC1708-SP

	9.0 __VOH SAT OUTPUT A,IOH=	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	2.5	2.5
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.670	1.710	0.040
1	113	1.663	1.720	0.057
1	114	1.662	1.710	0.048
5	115	1.673	1.727	0.054
5	118	1.695	1.732	0.037
5	119	1.657	1.727	0.070
0	123	1.670	1.729	0.060
0	124	1.695	1.724	0.030
	Max	1.695	1.732	0.070
	Average	1.673	1.722	0.050
	Min	1.657	1.710	0.030
	Std Dev	0.014	0.009	0.013



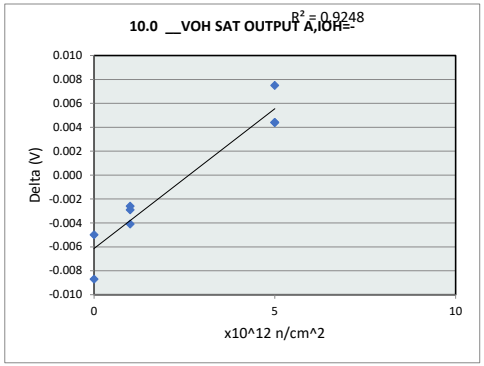
	9.0 __VOH SAT OUTPUT A,IOH		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2.5	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	1.725	1.710	1.727
Average	1.727	1.713	1.729
Max	1.729	1.720	1.732
UL	2.500	2.500	2.500



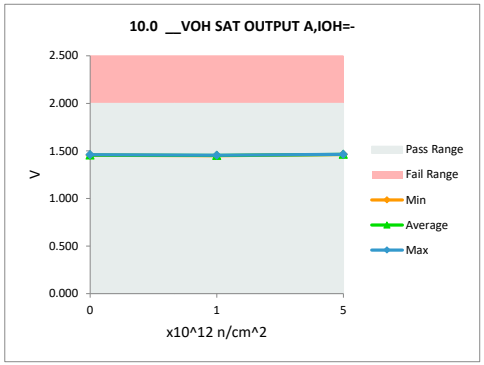
NDD Report
UC1708-SP

	10.0 __VOH SAT OUTPUT A,IOH=	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	2	2
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.454	1.450	-0.004
1	113	1.457	1.455	-0.003
1	114	1.455	1.452	-0.003
5	115	1.460	1.464	0.004
5	118	1.460	1.464	0.004
5	119	1.455	1.462	0.007
0	123	1.460	1.455	-0.005
0	124	1.469	1.460	-0.009
	Max	1.469	1.464	0.007
	Average	1.459	1.458	-0.001
	Min	1.454	1.450	-0.009
	Std Dev	0.005	0.006	0.006



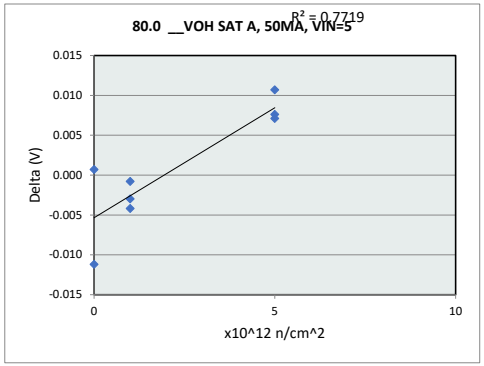
	10.0 __VOH SAT OUTPUT A,IO		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	1.455	1.450	1.462
Average	1.457	1.452	1.464
Max	1.460	1.455	1.464
UL	2.000	2.000	2.000



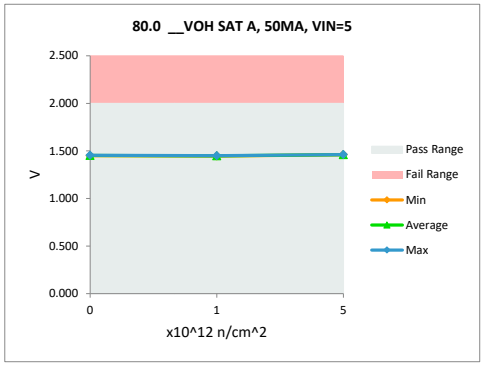
NDD Report
UC1708-SP

	80.0 __VOH SAT A, 50MA, VIN=5	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	2	2
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.450	1.446	-0.004
1	113	1.451	1.450	-0.001
1	114	1.452	1.449	-0.003
5	115	1.452	1.460	0.008
5	118	1.454	1.461	0.007
5	119	1.449	1.460	0.011
0	123	1.455	1.455	0.001
0	124	1.462	1.451	-0.011
	Max	1.462	1.461	0.011
	Average	1.453	1.454	0.001
	Min	1.449	1.446	-0.011
	Std Dev	0.004	0.006	0.007



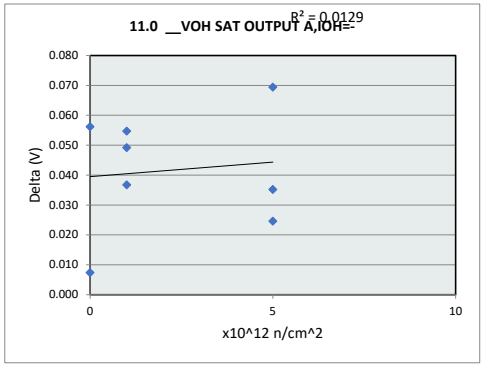
	80.0 __VOH SAT A, 50MA, VIN		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	1.451	1.446	1.460
Average	1.453	1.448	1.461
Max	1.455	1.450	1.461
UL	2.000	2.000	2.000



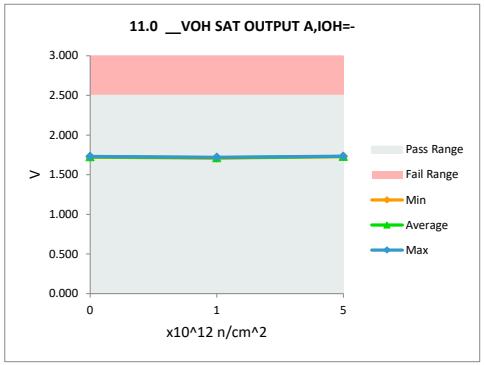
NDD Report
UC1708-SP

	11.0 __VOH SAT OUTPUT A,IOH=	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	2.5	2.5
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.677	1.714	0.037
1	113	1.665	1.720	0.055
1	114	1.660	1.709	0.049
5	115	1.693	1.728	0.035
5	118	1.709	1.734	0.025
5	119	1.659	1.728	0.069
0	123	1.675	1.731	0.056
0	124	1.714	1.721	0.007
	Max	1.714	1.734	0.069
	Average	1.681	1.723	0.042
	Min	1.659	1.709	0.007
	Std Dev	0.021	0.009	0.020



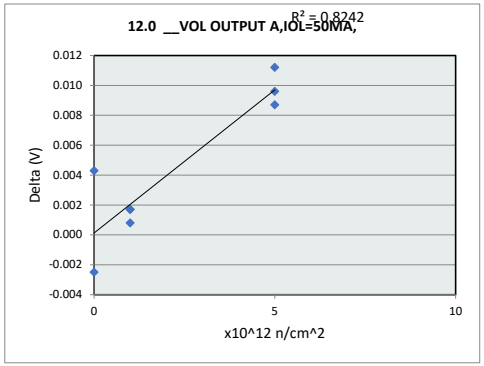
	11.0 __VOH SAT OUTPUT A,IO		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2.5	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	1.721	1.709	1.728
Average	1.726	1.714	1.730
Max	1.731	1.720	1.734
UL	2.500	2.500	2.500



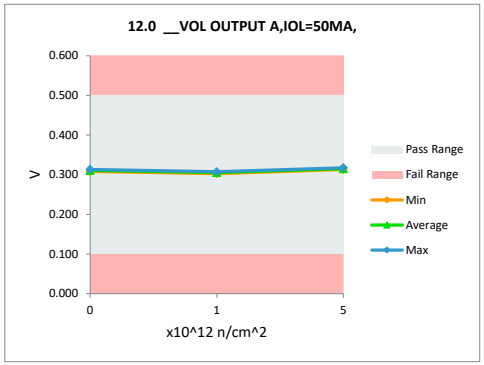
NDD Report
UC1708-SP

	12.0 __VOL OUTPUT A,IOL=50M	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	0.5	0.5
Min Limit	0.1	0.1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.304	0.306	0.002
1	113	0.301	0.303	0.002
1	114	0.307	0.308	0.001
5	115	0.305	0.315	0.010
5	118	0.302	0.313	0.011
5	119	0.309	0.317	0.009
0	123	0.309	0.313	0.004
0	124	0.311	0.308	-0.002
	Max	0.311	0.317	0.011
	Average	0.306	0.310	0.004
	Min	0.301	0.303	-0.002
	Std Dev	0.004	0.005	0.005



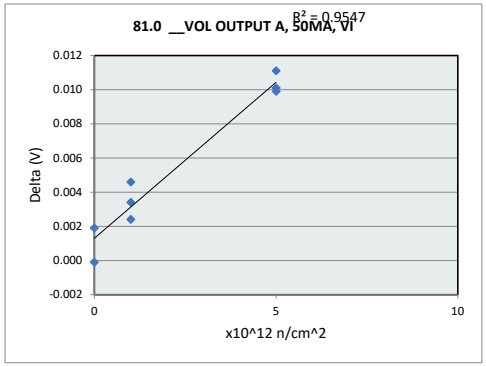
	12.0 __VOL OUTPUT A,IOL=50		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	0.5	V	
Min Limit	0.1	V	
x10^12 n/cm^2	0	1	5
LL	0.100	0.100	0.100
Min	0.309	0.303	0.313
Average	0.311	0.305	0.315
Max	0.313	0.308	0.317
UL	0.500	0.500	0.500



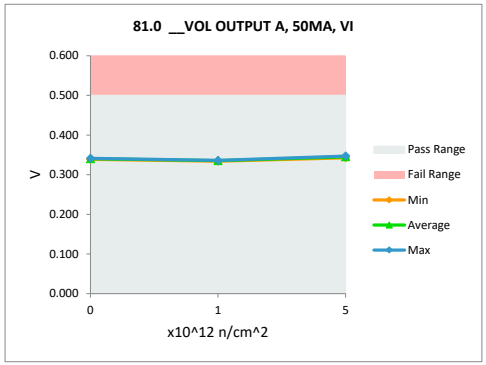
NDD Report
UC1708-SP

	81.0 __VOL OUTPUT A, 50MA, VI	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	0.5	0.5
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.334	0.336	0.002
1	113	0.331	0.334	0.003
1	114	0.332	0.336	0.005
5	115	0.334	0.345	0.011
5	118	0.333	0.343	0.010
5	119	0.337	0.347	0.010
0	123	0.340	0.342	0.002
0	124	0.339	0.339	0.000
	Max	0.340	0.347	0.011
	Average	0.335	0.340	0.005
	Min	0.331	0.334	0.000
	Std Dev	0.003	0.005	0.004



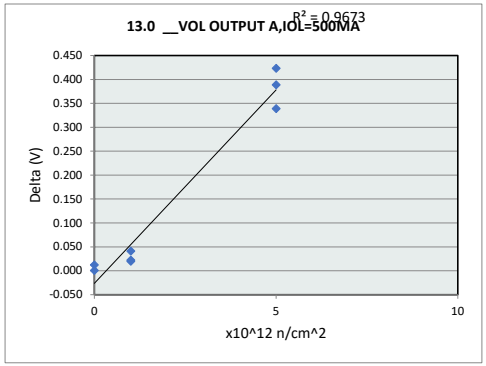
	81.0 __VOL OUTPUT A, 50MA,		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	0.5	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	0.339	0.334	0.343
Average	0.340	0.336	0.345
Max	0.342	0.336	0.347
UL	0.500	0.500	0.500



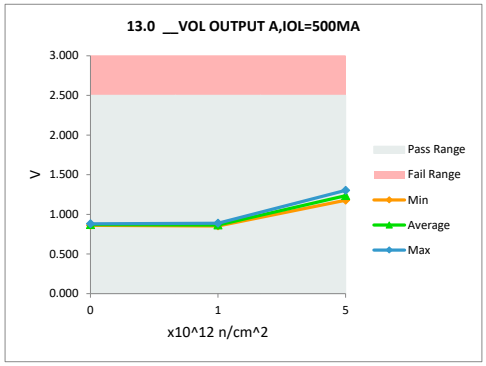
NDD Report
UC1708-SP

	13.0 __VOL OUTPUT A,IOL=500I	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	2.5	2.5
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.832	0.854	0.022
1	113	0.847	0.888	0.041
1	114	0.833	0.853	0.020
5	115	0.880	1.303	0.423
5	118	0.837	1.225	0.388
5	119	0.839	1.178	0.339
0	123	0.869	0.881	0.012
0	124	0.860	0.861	0.000
	Max	0.880	1.303	0.423
	Average	0.850	1.005	0.156
	Min	0.832	0.853	0.000
	Std Dev	0.018	0.194	0.190



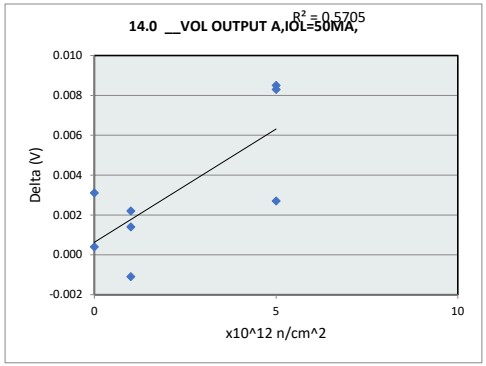
	13.0 __VOL OUTPUT A,IOL=50		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2.5	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	0.861	0.853	1.178
Average	0.871	0.865	1.235
Max	0.881	0.888	1.303
UL	2.500	2.500	2.500



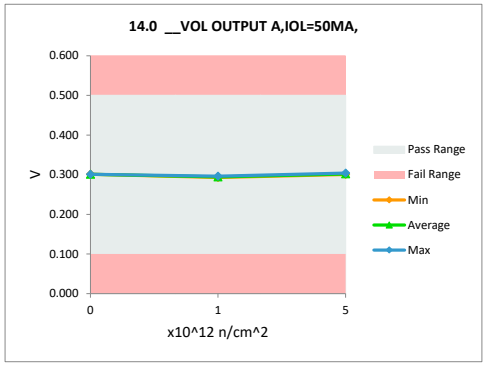
NDD Report
UC1708-SP

	14.0 __VOL OUTPUT A,IOL=50M	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	0.5	0.5
Min Limit	0.1	0.1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.293	0.294	0.001
1	113	0.291	0.293	0.002
1	114	0.297	0.296	-0.001
5	115	0.298	0.301	0.003
5	118	0.292	0.301	0.009
5	119	0.296	0.304	0.008
0	123	0.301	0.301	0.000
0	124	0.298	0.301	0.003
	Max	0.301	0.304	0.009
	Average	0.296	0.299	0.003
	Min	0.291	0.293	-0.001
	Std Dev	0.004	0.004	0.003



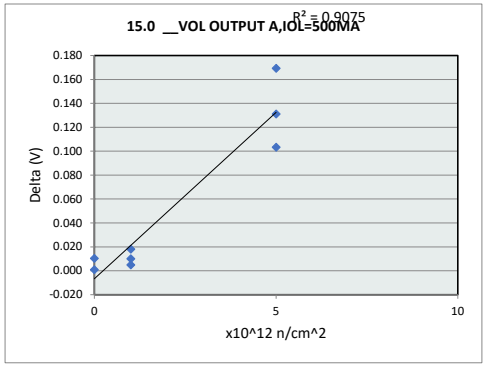
	14.0 __VOL OUTPUT A,IOL=50		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	0.5	V	
Min Limit	0.1	V	
x10^12 n/cm^2	0	1	5
LL	0.100	0.100	0.100
Min	0.301	0.293	0.301
Average	0.301	0.294	0.302
Max	0.301	0.296	0.304
UL	0.500	0.500	0.500



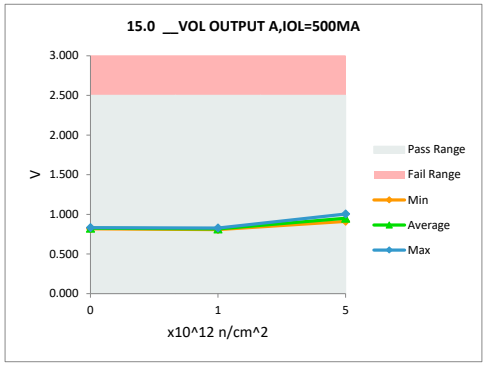
NDD Report
UC1708-SP

	15.0 __VOL OUTPUT A,IOL=500I	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	2.5	2.5
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.804	0.814	0.010
1	113	0.809	0.827	0.018
1	114	0.803	0.808	0.005
5	115	0.835	1.004	0.169
5	118	0.806	0.937	0.131
5	119	0.808	0.911	0.103
0	123	0.823	0.833	0.010
0	124	0.817	0.818	0.001
	Max	0.835	1.004	0.169
	Average	0.813	0.869	0.056
	Min	0.803	0.808	0.001
	Std Dev	0.011	0.073	0.068



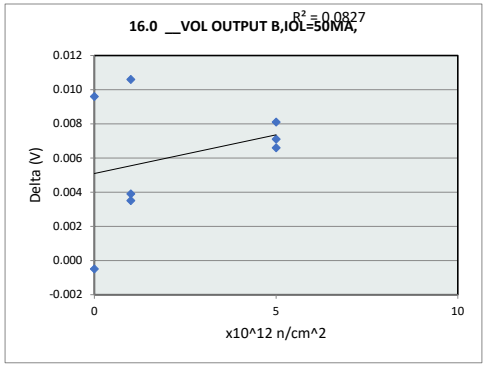
	15.0 __VOL OUTPUT A,IOL=50		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2.5	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	0.818	0.808	0.911
Average	0.826	0.816	0.951
Max	0.833	0.827	1.004
UL	2.500	2.500	2.500



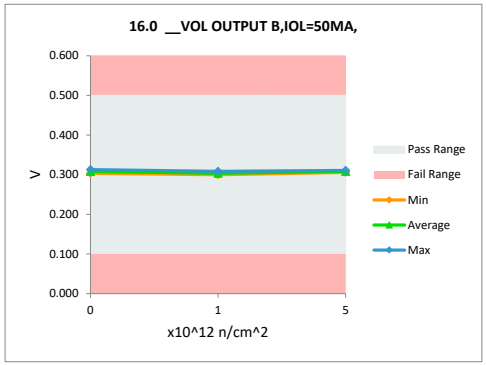
NDD Report
UC1708-SP

	16.0 __VOL OUTPUT B,IOL=50MA	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	0.5	0.5
Min Limit	0.1	0.1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.298	0.302	0.004
1	113	0.298	0.308	0.011
1	114	0.296	0.300	0.004
5	115	0.299	0.306	0.007
5	118	0.300	0.308	0.008
5	119	0.304	0.311	0.007
0	123	0.304	0.304	0.000
0	124	0.303	0.313	0.010
	Max	0.304	0.313	0.011
	Average	0.300	0.306	0.006
	Min	0.296	0.300	0.000
	Std Dev	0.003	0.004	0.004



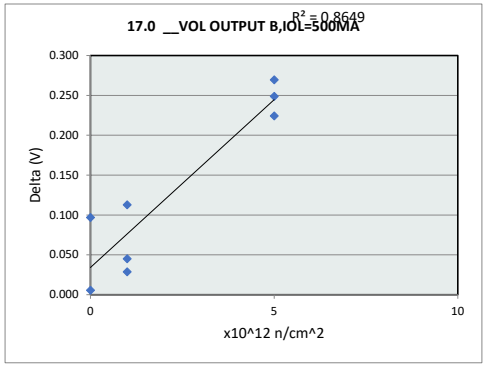
	16.0 __VOL OUTPUT B,IOL=50		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	0.5	V	
Min Limit	0.1	V	
x10^12 n/cm^2	0	1	5
LL	0.100	0.100	0.100
Min	0.304	0.300	0.306
Average	0.308	0.304	0.308
Max	0.313	0.309	0.311
UL	0.500	0.500	0.500



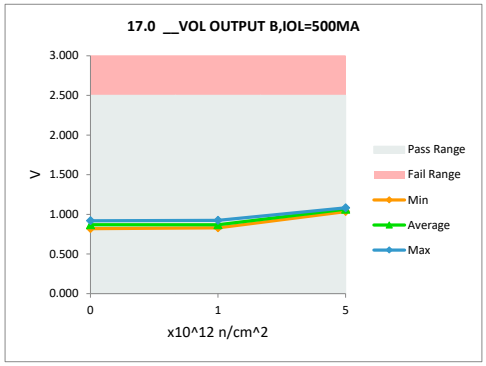
NDD Report
UC1708-SP

	17.0 __VOL OUTPUT B,IOL=500M	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	2.5	2.5
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.811	0.856	0.045
1	113	0.811	0.923	0.113
1	114	0.800	0.829	0.029
5	115	0.830	1.078	0.249
5	118	0.813	1.082	0.269
5	119	0.810	1.034	0.224
0	123	0.814	0.819	0.005
0	124	0.822	0.919	0.097
	Max	0.830	1.082	0.269
	Average	0.814	0.943	0.129
	Min	0.800	0.819	0.005
	Std Dev	0.009	0.109	0.105



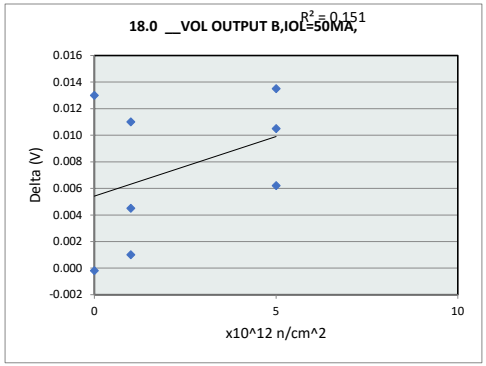
	17.0 __VOL OUTPUT B,IOL=50		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2.5	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	0.819	0.829	1.034
Average	0.869	0.869	1.065
Max	0.919	0.923	1.082
UL	2.500	2.500	2.500



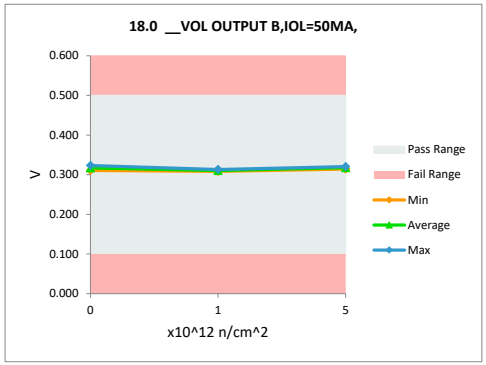
NDD Report
UC1708-SP

	18.0 __VOL OUTPUT B,IOL=50MA	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	0.5	0.5
Min Limit	0.1	0.1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.305	0.310	0.005
1	113	0.302	0.313	0.011
1	114	0.308	0.308	0.001
5	115	0.308	0.314	0.006
5	118	0.305	0.318	0.014
5	119	0.310	0.320	0.010
0	123	0.311	0.311	0.000
0	124	0.310	0.323	0.013
	Max	0.311	0.323	0.014
	Average	0.307	0.315	0.007
	Min	0.302	0.308	0.000
	Std Dev	0.003	0.005	0.005



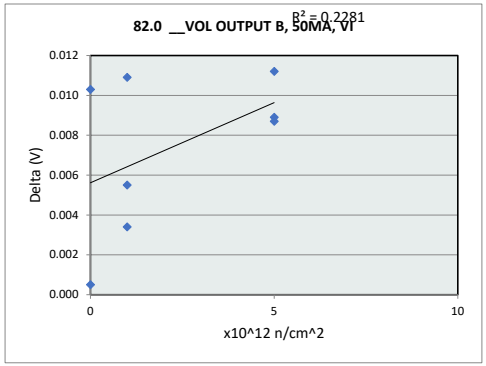
	18.0 __VOL OUTPUT B,IOL=50		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	0.5	V	
Min Limit	0.1	V	
x10^12 n/cm^2	0	1	5
LL	0.100	0.100	0.100
Min	0.311	0.309	0.314
Average	0.317	0.310	0.318
Max	0.323	0.313	0.321
UL	0.500	0.500	0.500



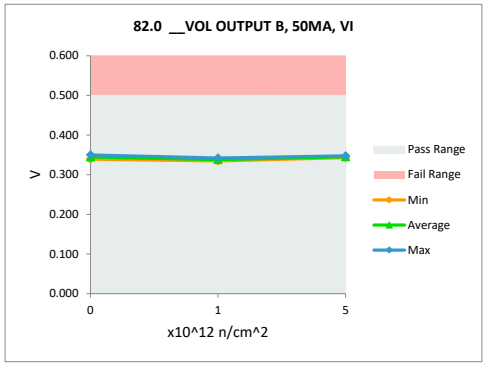
NDD Report
UC1708-SP

	82.0 __VOL OUTPUT B, 50MA, VI	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	0.5	0.5
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.332	0.337	0.005
1	113	0.331	0.342	0.011
1	114	0.331	0.335	0.003
5	115	0.334	0.343	0.009
5	118	0.334	0.345	0.011
5	119	0.339	0.348	0.009
0	123	0.339	0.339	0.000
0	124	0.340	0.350	0.010
	Max	0.340	0.350	0.011
	Average	0.335	0.342	0.007
	Min	0.331	0.335	0.000
	Std Dev	0.004	0.005	0.004



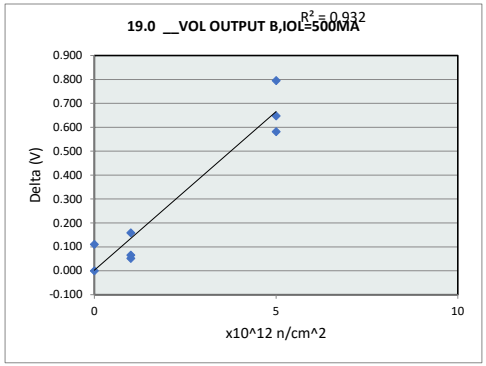
	82.0 __VOL OUTPUT B, 50MA,		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	0.5	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	0.339	0.335	0.343
Average	0.345	0.338	0.345
Max	0.350	0.342	0.348
UL	0.500	0.500	0.500



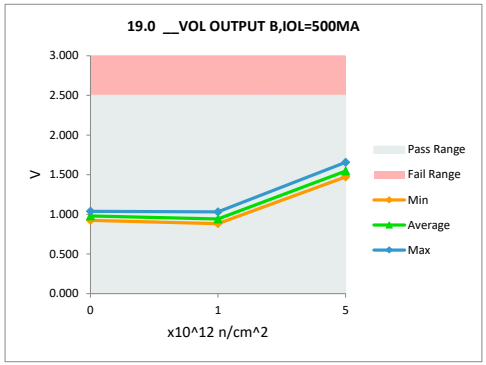
NDD Report
UC1708-SP

	19.0 __VOL OUTPUT B,IOL=500M	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	2.5	2.5
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.846	0.912	0.065
1	113	0.873	1.031	0.158
1	114	0.831	0.882	0.051
5	115	0.891	1.472	0.581
5	118	0.862	1.509	0.647
5	119	0.862	1.656	0.795
0	123	0.924	0.923	-0.001
0	124	0.927	1.037	0.110
	Max	0.927	1.656	0.795
	Average	0.877	1.178	0.301
	Min	0.831	0.882	-0.001
	Std Dev	0.035	0.314	0.318



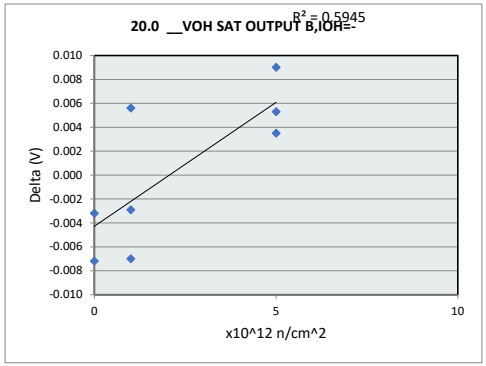
	19.0 __VOL OUTPUT B,IOL=50		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2.5	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	0.923	0.882	1.472
Average	0.980	0.942	1.546
Max	1.037	1.031	1.656
UL	2.500	2.500	2.500



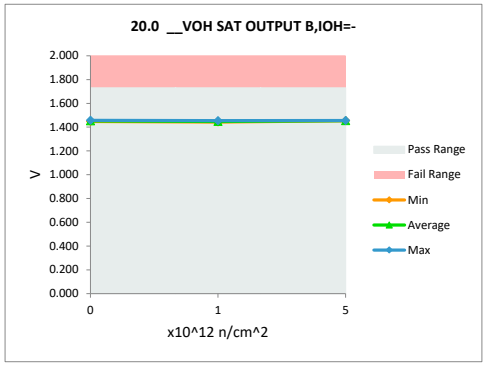
NDD Report
UC1708-SP

	20.0 __VOH SAT OUTPUT B,IOH=	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	1.73	1.73
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.447	1.445	-0.003
1	113	1.449	1.455	0.006
1	114	1.450	1.443	-0.007
5	115	1.450	1.454	0.003
5	118	1.451	1.456	0.005
5	119	1.445	1.454	0.009
0	123	1.454	1.447	-0.007
0	124	1.460	1.457	-0.003
	Max	1.460	1.457	0.009
	Average	1.451	1.451	0.000
	Min	1.445	1.443	-0.007
	Std Dev	0.005	0.006	0.006



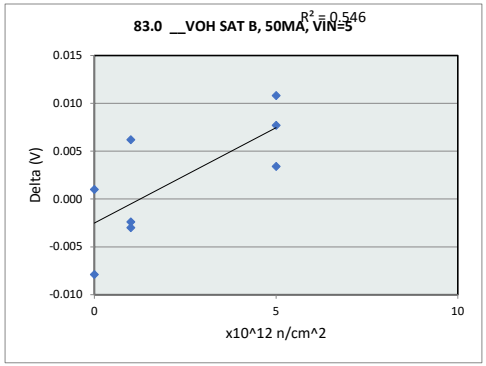
	20.0 __VOH SAT OUTPUT B,IO		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	1.73	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	1.447	1.443	1.454
Average	1.452	1.447	1.455
Max	1.457	1.455	1.456
UL	1.730	1.730	1.730



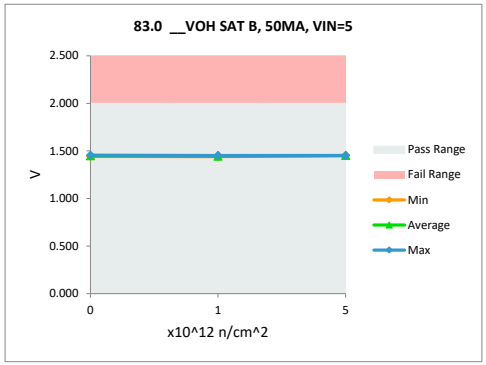
NDD Report
UC1708-SP

	83.0 __VOH SAT B, 50MA, VIN=5	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	2	2
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.444	1.441	-0.003
1	113	1.445	1.452	0.006
1	114	1.443	1.440	-0.002
5	115	1.447	1.451	0.003
5	118	1.445	1.453	0.008
5	119	1.440	1.451	0.011
0	123	1.451	1.443	-0.008
0	124	1.454	1.455	0.001
	Max	1.454	1.455	0.011
	Average	1.446	1.448	0.002
	Min	1.440	1.440	-0.008
	Std Dev	0.005	0.006	0.006

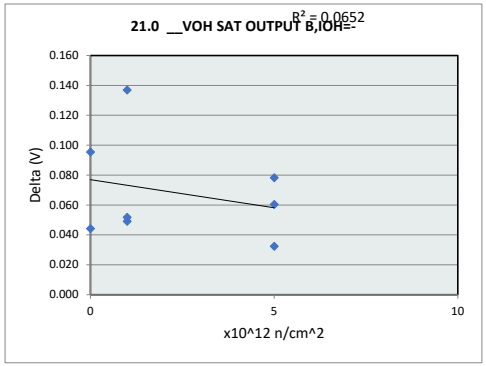


	83.0 __VOH SAT B, 50MA, VIN		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	1.443	1.440	1.451
Average	1.449	1.444	1.451
Max	1.455	1.452	1.453
UL	2.000	2.000	2.000

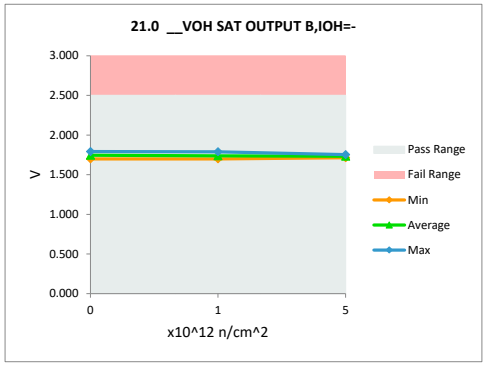


NDD Report
UC1708-SP

		21.0 __VOH SAT OUTPUT B,IOH=	
Test Site		MTT	MTT
Tester		LTX	LTX
Test Number		XPM02903	XPM02903
Unit		V	V
Max Limit		2.5	2.5
Min Limit		0	0
x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.672	1.724	0.052
1	113	1.653	1.789	0.137
1	114	1.650	1.699	0.049
5	115	1.682	1.714	0.032
5	118	1.693	1.753	0.060
5	119	1.653	1.731	0.078
0	123	1.655	1.699	0.044
0	124	1.697	1.792	0.095
	Max	1.697	1.792	0.137
	Average	1.669	1.738	0.068
	Min	1.650	1.699	0.032
	Std Dev	0.019	0.037	0.034



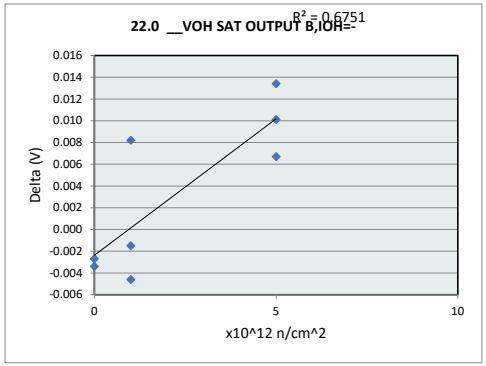
		21.0 __VOH SAT OUTPUT B,IO		
Test Site		MTT		
Tester		LTX		
Test Number		XPM02903		
Max Limit		2.5	V	
Min Limit		0	V	
x10^12 n/cm^2		0	1	5
	LL	0.000	0.000	0.000
	Min	1.699	1.699	1.714
	Average	1.746	1.737	1.733
	Max	1.792	1.790	1.754
	UL	2.500	2.500	2.500



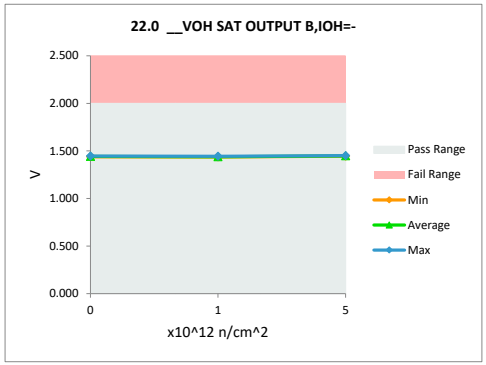
NDD Report
UC1708-SP

	22.0 __VOH SAT OUTPUT B,IOH=	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	2	2
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.438	1.436	-0.002
1	113	1.436	1.444	0.008
1	114	1.441	1.436	-0.005
5	115	1.438	1.445	0.007
5	118	1.441	1.451	0.010
5	119	1.433	1.446	0.013
0	123	1.442	1.439	-0.003
0	124	1.449	1.446	-0.003
	Max	1.449	1.451	0.013
	Average	1.440	1.443	0.003
	Min	1.433	1.436	-0.005
	Std Dev	0.005	0.005	0.007



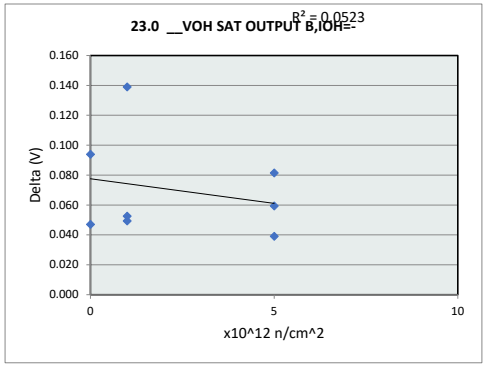
	22.0 __VOH SAT OUTPUT B,IO		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	1.439	1.436	1.445
Average	1.442	1.439	1.447
Max	1.446	1.444	1.451
UL	2.000	2.000	2.000



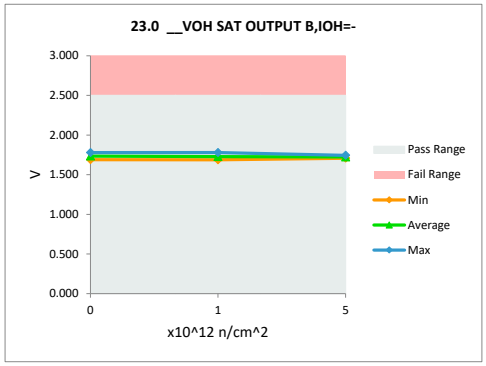
NDD Report
UC1708-SP

	23.0 __VOH SAT OUTPUT B,IOH=	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	2.5	2.5
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.663	1.715	0.053
1	113	1.641	1.780	0.139
1	114	1.639	1.688	0.049
5	115	1.669	1.708	0.039
5	118	1.685	1.744	0.059
5	119	1.639	1.721	0.081
0	123	1.644	1.691	0.047
0	124	1.685	1.779	0.094
	Max	1.685	1.780	0.139
	Average	1.658	1.728	0.070
	Min	1.639	1.688	0.039
	Std Dev	0.020	0.036	0.033



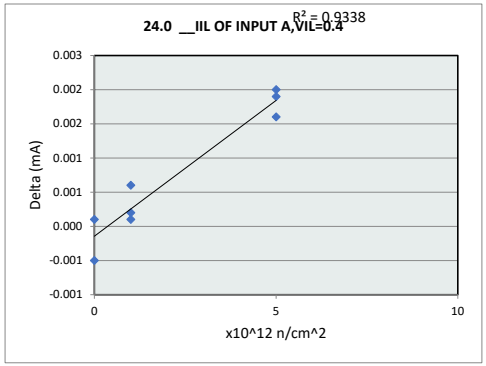
	23.0 __VOH SAT OUTPUT B,IO		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2.5	V	
Min Limit	0	V	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	1.691	1.688	1.708
Average	1.735	1.728	1.724
Max	1.779	1.780	1.744
UL	2.500	2.500	2.500



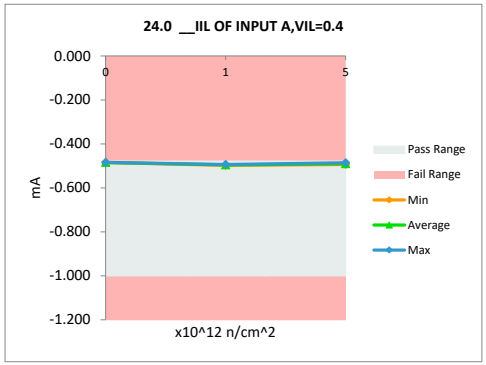
NDD Report
UC1708-SP

	24.0 __IIL OF INPUT A,VIL=0.4	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	-0.475	-0.475
Min Limit	-1	-1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	-0.498	-0.498	0.000
1	113	-0.496	-0.496	0.000
1	114	-0.494	-0.494	0.001
5	115	-0.492	-0.490	0.002
5	118	-0.496	-0.494	0.002
5	119	-0.487	-0.485	0.002
0	123	-0.485	-0.485	0.000
0	124	-0.484	-0.484	-0.001
	Max	-0.484	-0.484	0.002
	Average	-0.491	-0.491	0.001
	Min	-0.498	-0.498	-0.001
	Std Dev	0.006	0.005	0.001



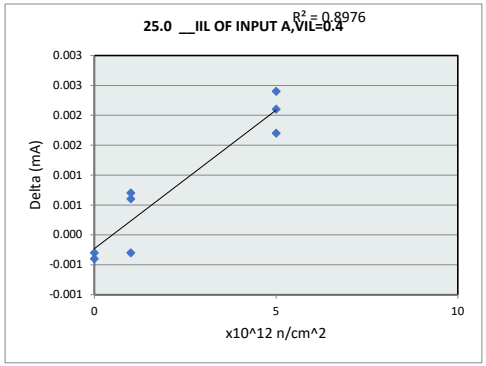
	24.0 __IIL OF INPUT A,VIL=0.		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	-0.475	mA	
Min Limit	-1	mA	
x10^12 n/cm^2	0	1	5
LL	-1.000	-1.000	-1.000
Min	-0.485	-0.498	-0.494
Average	-0.484	-0.496	-0.490
Max	-0.484	-0.494	-0.485
UL	-0.475	-0.475	-0.475



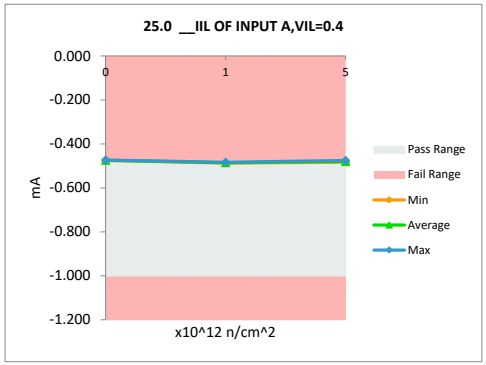
NDD Report
UC1708-SP

	25.0 __IIL OF INPUT A,VIL=0.4	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	-0.475	-0.475
Min Limit	-1	-1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	-0.488	-0.487	0.001
1	113	-0.486	-0.486	0.000
1	114	-0.484	-0.484	0.001
5	115	-0.482	-0.480	0.002
5	118	-0.486	-0.484	0.002
5	119	-0.477	-0.475	0.002
0	123	-0.475	-0.475	0.000
0	124	-0.473	-0.474	0.000
	Max	-0.473	-0.474	0.002
	Average	-0.481	-0.481	0.001
	Min	-0.488	-0.487	0.000
	Std Dev	0.006	0.005	0.001



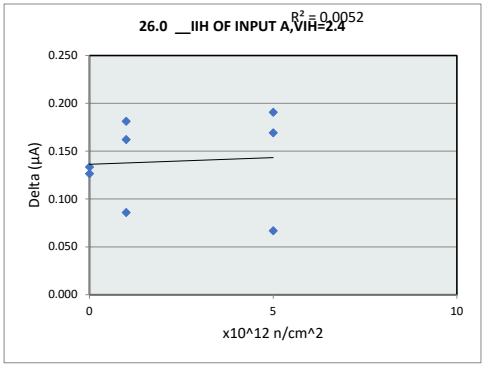
	25.0 __IIL OF INPUT A,VIL=0.		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	-0.475	mA	
Min Limit	-1	mA	
x10^12 n/cm^2	0	1	5
LL	-1.000	-1.000	-1.000
Min	-0.475	-0.487	-0.484
Average	-0.474	-0.486	-0.479
Max	-0.474	-0.484	-0.475
UL	-0.475	-0.475	-0.475



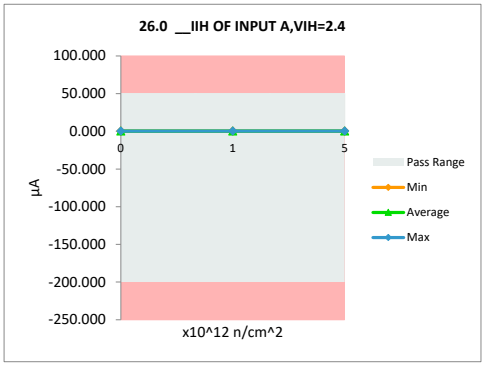
NDD Report
UC1708-SP

	26.0 __IIH OF INPUT A,VIH=2.4	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	50	50
Min Limit	-200	-200

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.122	0.303	0.181
1	113	0.143	0.229	0.086
1	114	0.179	0.341	0.162
5	115	0.162	0.229	0.067
5	118	0.122	0.312	0.191
5	119	0.131	0.300	0.169
0	123	0.119	0.245	0.126
0	124	0.162	0.296	0.134
	Max	0.179	0.341	0.191
	Average	0.142	0.282	0.139
	Min	0.119	0.229	0.067
	Std Dev	0.023	0.042	0.045



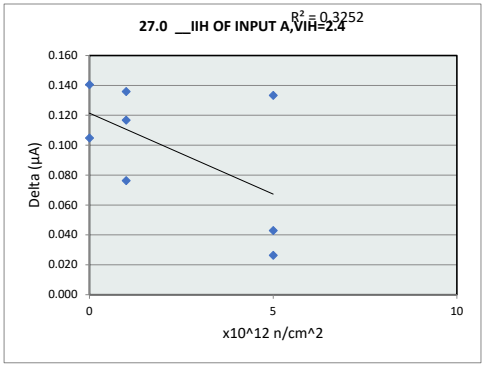
	26.0 __IIH OF INPUT A,VIH=2		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	50	µA	
Min Limit	-200	µA	
x10^12 n/cm^2	0	1	5
LL	-200.000	-200.000	-200.000
Min	0.245	0.229	0.229
Average	0.270	0.291	0.280
Max	0.296	0.341	0.312
UL	50.000	50.000	50.000



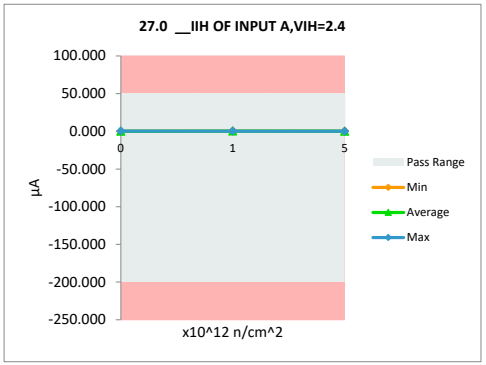
NDD Report
UC1708-SP

	27.0 __IIH OF INPUT A,VIH=2.4	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	50	50
Min Limit	-200	-200

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.114	0.231	0.117
1	113	0.153	0.229	0.076
1	114	0.083	0.219	0.136
5	115	0.143	0.169	0.026
5	118	0.126	0.169	0.043
5	119	0.055	0.188	0.133
0	123	0.114	0.219	0.105
0	124	0.048	0.188	0.140
	Max	0.153	0.231	0.140
	Average	0.105	0.202	0.097
	Min	0.048	0.169	0.026
	Std Dev	0.039	0.026	0.044



	27.0 __IIH OF INPUT A,VIH=2		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	50	µA	
Min Limit	-200	µA	
x10^12 n/cm^2	0	1	5
LL	-200.000	-200.000	-200.000
Min	0.188	0.219	0.169
Average	0.204	0.226	0.176
Max	0.219	0.231	0.188
UL	50.000	50.000	50.000



NDD Report
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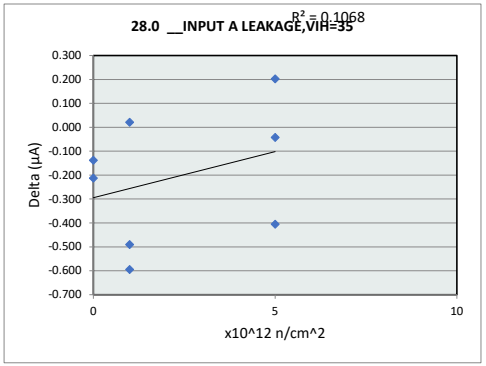
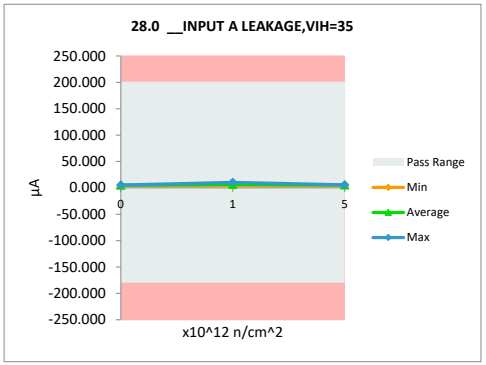
	28.0 __INPUT A LEAKAGE,VIH=3	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	200	200
Min Limit	-180	-180

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	5.203	4.607	-0.595
1	113	10.342	10.362	0.020
1	114	5.120	4.629	-0.491
5	115	5.550	5.753	0.202
5	118	4.901	4.495	-0.405
5	119	5.469	5.426	-0.043
0	123	5.529	5.391	-0.138
0	124	4.863	4.650	-0.213
	Max	10.342	10.362	0.202
	Average	5.872	5.664	-0.208
	Min	4.863	4.495	-0.595
	Std Dev	1.826	1.956	0.273



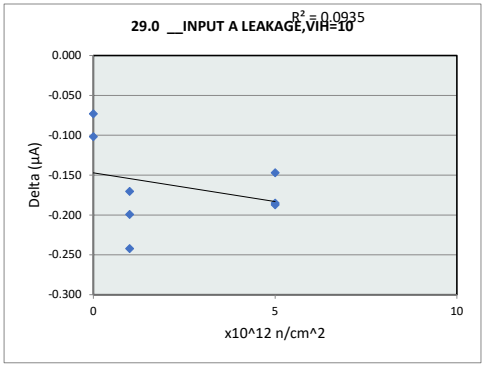
	28.0 __INPUT A LEAKAGE,VIH=		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	200	µA	
Min Limit	-180	µA	
x10^12 n/cm^2	0	1	5
LL	-180.000	-180.000	-180.000
Min	4.650	4.607	4.495
Average	5.020	6.533	5.225
Max	5.391	10.362	5.753
UL	200.000	200.000	200.000



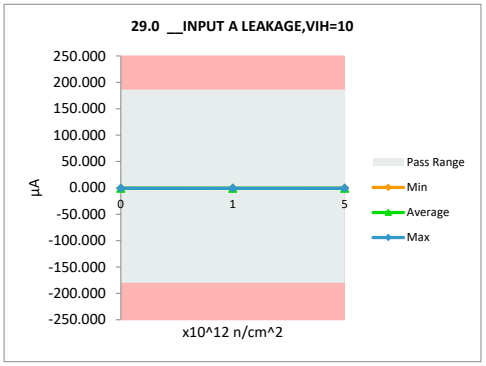
NDD Report
UC1708-SP

	29.0 __INPUT A LEAKAGE,VIH=1	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	185	185
Min Limit	-180	-180

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	-0.608	-0.808	-0.199
1	113	-0.639	-0.882	-0.242
1	114	-0.601	-0.772	-0.170
5	115	-0.706	-0.853	-0.147
5	118	-0.601	-0.789	-0.187
5	119	-0.639	-0.825	-0.185
0	123	-0.668	-0.770	-0.102
0	124	-0.692	-0.765	-0.073
	Max	-0.601	-0.765	-0.073
	Average	-0.644	-0.808	-0.163
	Min	-0.706	-0.882	-0.242
	Std Dev	0.041	0.043	0.055



	29.0 __INPUT A LEAKAGE,VIH=		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	185	µA	
Min Limit	-180	µA	
x10^12 n/cm^2	0	1	5
LL	-180.000	-180.000	-180.000
Min	-0.770	-0.882	-0.853
Average	-0.767	-0.820	-0.822
Max	-0.765	-0.772	-0.789
UL	185.000	185.000	185.000



NDD Report
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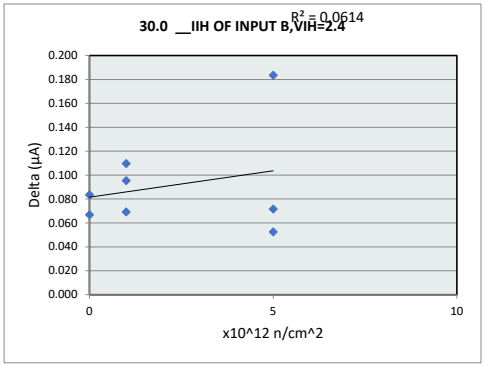
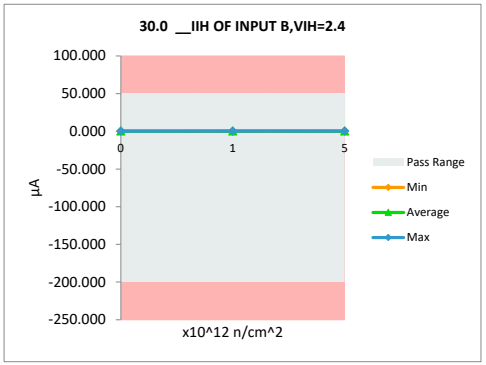
	30.0 __IIH OF INPUT B,VIH=2.4	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	50	50
Min Limit	-200	-200

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.122	0.231	0.110
1	113	0.119	0.188	0.069
1	114	0.191	0.286	0.095
5	115	0.179	0.231	0.052
5	118	0.157	0.229	0.072
5	119	0.083	0.267	0.183
0	123	0.122	0.188	0.067
0	124	0.162	0.245	0.083
	Max	0.191	0.286	0.183
	Average	0.142	0.233	0.091
	Min	0.083	0.188	0.052
	Std Dev	0.036	0.034	0.041



	30.0 __IIH OF INPUT B,VIH=2		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	50	µA	
Min Limit	-200	µA	
x10^12 n/cm^2	0	1	5
LL	-200.000	-200.000	-200.000
Min	0.188	0.188	0.229
Average	0.217	0.235	0.242
Max	0.245	0.286	0.267
UL	50.000	50.000	50.000



NDD Report
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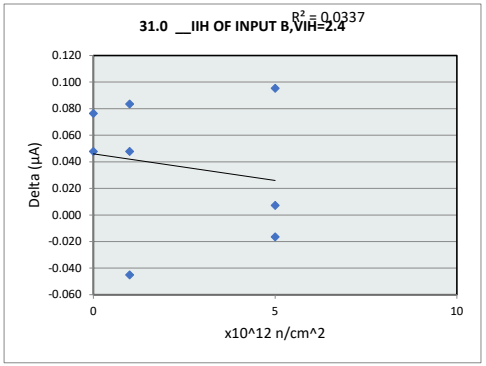
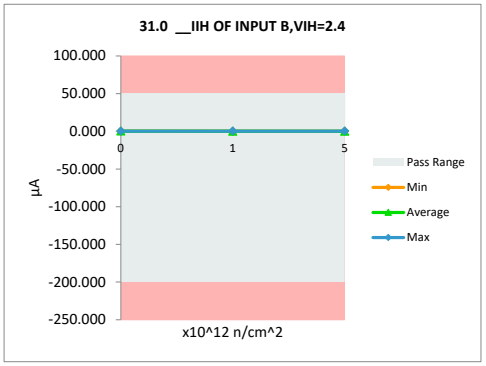
	31.0 __IIH OF INPUT B,VIH=2.4		
Test Site	MTT	MTT	
Tester	LTX	LTX	
Test Number	XPM02903	XPM02903	
Unit	µA	µA	
Max Limit	50	50	
Min Limit	-200	-200	
x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.122	0.169	0.048
1	113	0.145	0.229	0.083
1	114	0.162	0.117	-0.045
5	115	0.114	0.210	0.095
5	118	0.162	0.169	0.007
5	119	0.169	0.153	-0.017
0	123	0.153	0.229	0.076
0	124	0.162	0.210	0.048
	Max	0.169	0.229	0.095
	Average	0.149	0.186	0.037
	Min	0.114	0.117	-0.045
	Std Dev	0.020	0.040	0.051



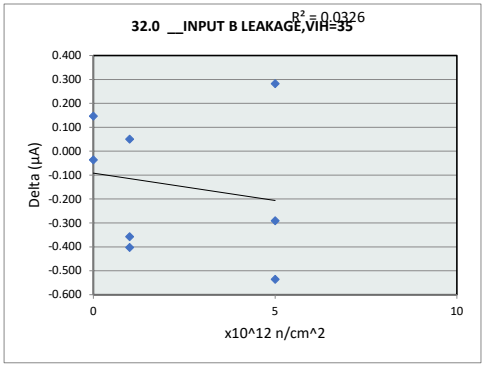
	31.0 __IIH OF INPUT B,VIH=2		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	50	µA	
Min Limit	-200	µA	
x10^12 n/cm^2	0	1	5
LL	-200.000	-200.000	-200.000
Min	0.210	0.117	0.153
Average	0.219	0.172	0.177
Max	0.229	0.229	0.210
UL	50.000	50.000	50.000



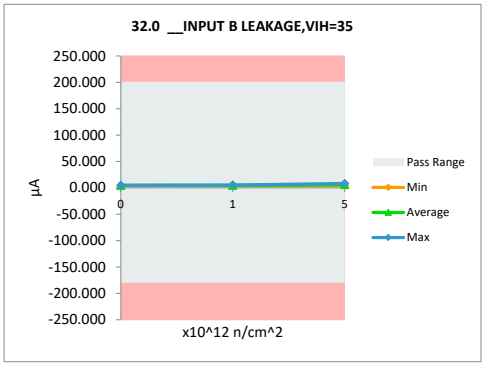
NDD Report
UC1708-SP

	32.0 __INPUT B LEAKAGE,VIH=3	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	200	200
Min Limit	-180	-180

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	4.955	4.553	-0.403
1	113	5.360	5.410	0.050
1	114	4.853	4.495	-0.358
5	115	4.946	4.655	-0.291
5	118	4.518	4.800	0.282
5	119	8.858	8.322	-0.536
0	123	4.844	4.807	-0.036
0	124	4.539	4.686	0.146
	Max	8.858	8.322	0.282
	Average	5.359	5.216	-0.143
	Min	4.518	4.495	-0.536
	Std Dev	1.438	1.286	0.294



	32.0 __INPUT B LEAKAGE,VIH=		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	200	µA	
Min Limit	-180	µA	
x10^12 n/cm^2	0	1	5
LL	-180.000	-180.000	-180.000
Min	4.686	4.495	4.655
Average	4.747	4.819	5.926
Max	4.807	5.410	8.322
UL	200.000	200.000	200.000



NDD Report
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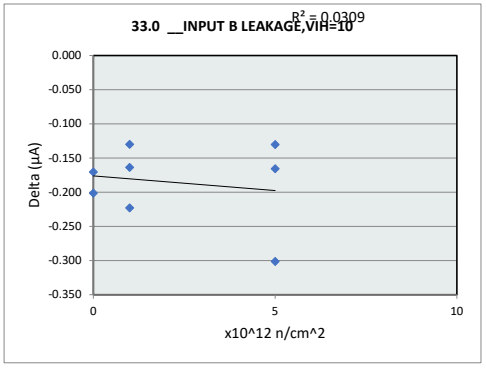
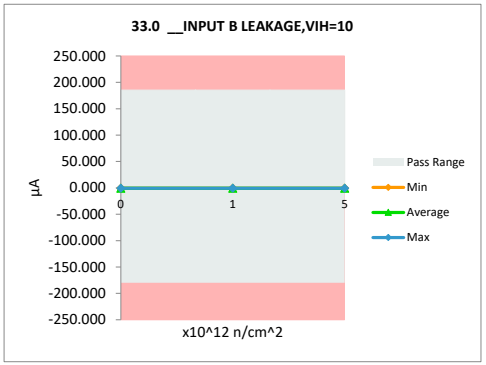
	33.0 __INPUT B LEAKAGE,VIH=1	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	185	185
Min Limit	-180	-180

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	-0.601	-0.732	-0.130
1	113	-0.639	-0.803	-0.164
1	114	-0.601	-0.825	-0.223
5	115	-0.640	-0.805	-0.166
5	118	-0.639	-0.770	-0.130
5	119	-0.542	-0.844	-0.302
0	123	-0.561	-0.732	-0.171
0	124	-0.601	-0.803	-0.201
	Max	-0.542	-0.732	-0.130
	Average	-0.603	-0.789	-0.186
	Min	-0.640	-0.844	-0.302
	Std Dev	0.037	0.041	0.056



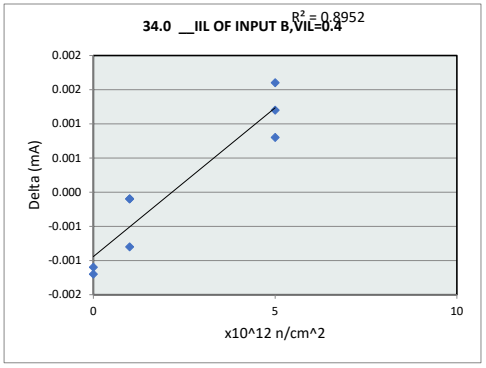
	33.0 __INPUT B LEAKAGE,VIH=		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	185	µA	
Min Limit	-180	µA	
x10^12 n/cm^2	0	1	5
LL	-180.000	-180.000	-180.000
Min	-0.803	-0.825	-0.844
Average	-0.767	-0.786	-0.806
Max	-0.732	-0.732	-0.770
UL	185.000	185.000	185.000



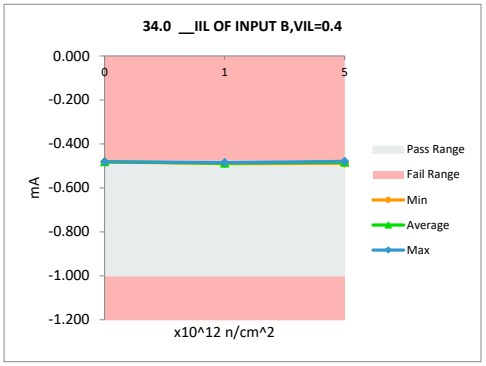
NDD Report
UC1708-SP

	34.0 __IIL OF INPUT B,VIL=0.4	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	-0.475	-0.475
Min Limit	-1	-1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	-0.488	-0.488	0.000
1	113	-0.489	-0.490	-0.001
1	114	-0.485	-0.485	0.000
5	115	-0.483	-0.481	0.002
5	118	-0.490	-0.489	0.001
5	119	-0.480	-0.480	0.001
0	123	-0.481	-0.482	-0.001
0	124	-0.480	-0.481	-0.001
	Max	-0.480	-0.480	0.002
	Average	-0.484	-0.484	0.000
	Min	-0.490	-0.490	-0.001
	Std Dev	0.004	0.004	0.001



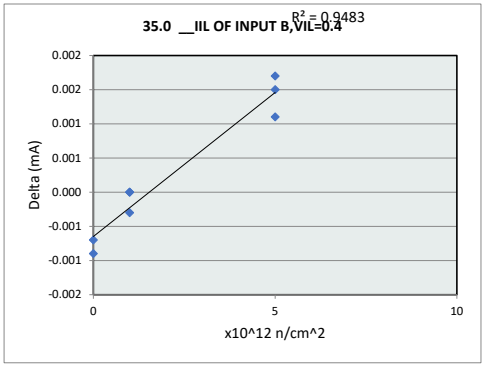
	34.0 __IIL OF INPUT B,VIL=0.		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	-0.475	mA	
Min Limit	-1	mA	
x10^12 n/cm^2	0	1	5
LL	-1.000	-1.000	-1.000
Min	-0.482	-0.490	-0.489
Average	-0.481	-0.488	-0.483
Max	-0.481	-0.485	-0.480
UL	-0.475	-0.475	-0.475



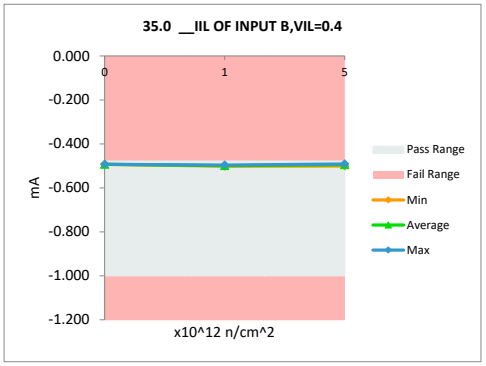
NDD Report
UC1708-SP

	35.0 __IIL OF INPUT B,VIL=0.4	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	-0.475	-0.475
Min Limit	-1	-1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	-0.500	-0.500	0.000
1	113	-0.501	-0.501	0.000
1	114	-0.496	-0.496	0.000
5	115	-0.494	-0.493	0.002
5	118	-0.502	-0.500	0.002
5	119	-0.492	-0.491	0.001
0	123	-0.492	-0.493	-0.001
0	124	-0.492	-0.493	-0.001
	Max	-0.492	-0.491	0.002
	Average	-0.496	-0.496	0.000
	Min	-0.502	-0.501	-0.001
	Std Dev	0.004	0.004	0.001



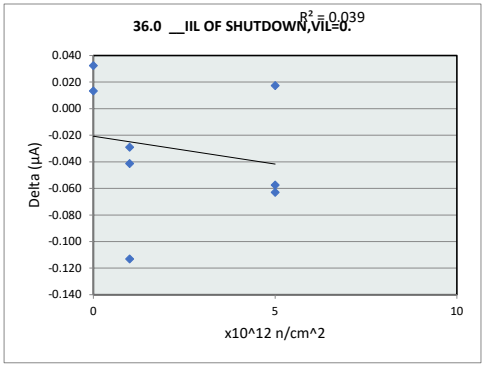
	35.0 __IIL OF INPUT B,VIL=0.		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	-0.475	mA	
Min Limit	-1	mA	
x10^12 n/cm^2	0	1	5
LL	-1.000	-1.000	-1.000
Min	-0.493	-0.501	-0.500
Average	-0.493	-0.499	-0.495
Max	-0.493	-0.496	-0.491
UL	-0.475	-0.475	-0.475



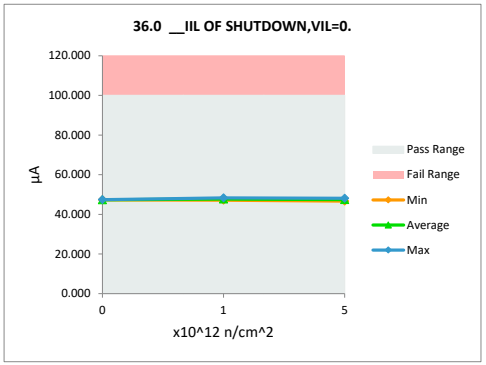
NDD Report
UC1708-SP

	36.0 __IIL OF SHUTDOWN,VIL=(	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	100	100
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	47.752	47.723	-0.029
1	113	48.347	48.305	-0.041
1	114	47.217	47.104	-0.113
5	115	47.649	47.591	-0.058
5	118	48.185	48.122	-0.063
5	119	46.663	46.681	0.017
0	123	47.368	47.401	0.032
0	124	47.302	47.315	0.013
	Max	48.347	48.305	0.032
	Average	47.560	47.530	-0.030
	Min	46.663	46.681	-0.113
	Std Dev	0.545	0.529	0.049



	36.0 __IIL OF SHUTDOWN,VIL		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	100	µA	
Min Limit	0	µA	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	47.315	47.104	46.681
Average	47.358	47.711	47.465
Max	47.401	48.305	48.122
UL	100.000	100.000	100.000



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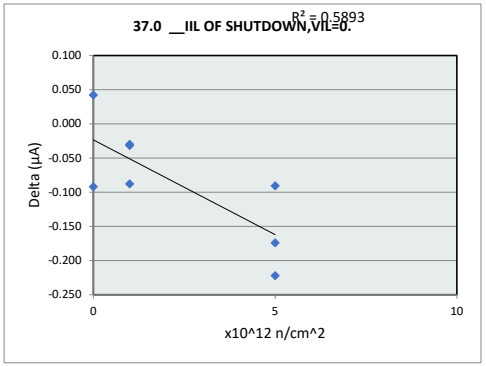
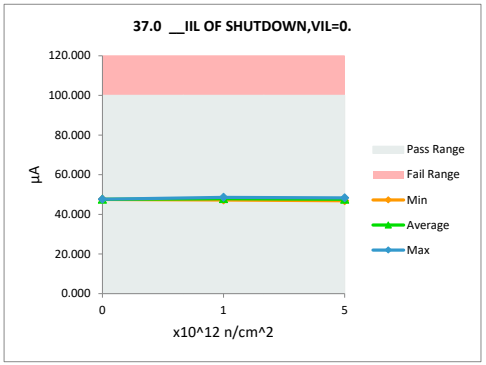
	37.0 __IIL OF SHUTDOWN,VIL=0	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	100	100
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	47.896	47.866	-0.030
1	113	48.584	48.552	-0.032
1	114	47.340	47.252	-0.088
5	115	47.937	47.763	-0.174
5	118	48.499	48.277	-0.222
5	119	46.959	46.869	-0.091
0	123	47.611	47.519	-0.092
0	124	47.595	47.638	0.042
	Max	48.584	48.552	0.042
	Average	47.803	47.717	-0.086
	Min	46.959	46.869	-0.222
	Std Dev	0.551	0.537	0.084



	37.0 __IIL OF SHUTDOWN,VIL		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	100	µA	
Min Limit	0	µA	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	47.519	47.252	46.869
Average	47.578	47.890	47.636
Max	47.638	48.552	48.277
UL	100.000	100.000	100.000



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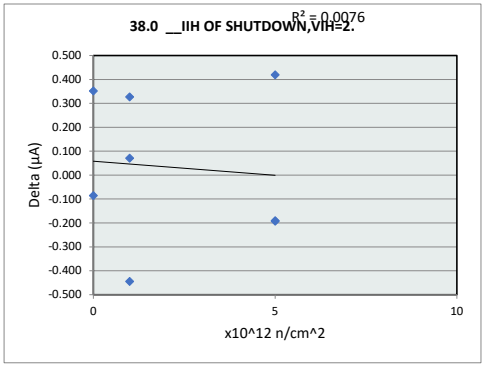
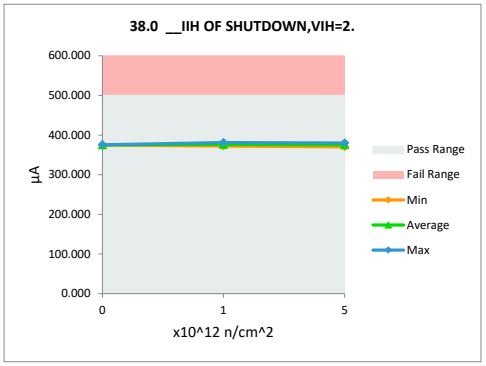
	38.0 __IIH OF SHUTDOWN,VIH=	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	500	500
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	376.496	376.567	0.070
1	113	380.789	381.115	0.326
1	114	372.716	372.272	-0.444
5	115	376.948	376.755	-0.193
5	118	380.408	380.217	-0.191
5	119	369.976	370.395	0.419
0	123	375.124	375.475	0.352
0	124	375.025	374.939	-0.086
	Max	380.789	381.115	0.419
	Average	375.935	375.967	0.032
	Min	369.976	370.395	-0.444
	Std Dev	3.631	3.616	0.312



	38.0 __IIH OF SHUTDOWN,VIH		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	500	µA	
Min Limit	0	µA	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	374.939	372.272	370.395
Average	375.207	376.651	375.789
Max	375.475	381.115	380.217
UL	500.000	500.000	500.000



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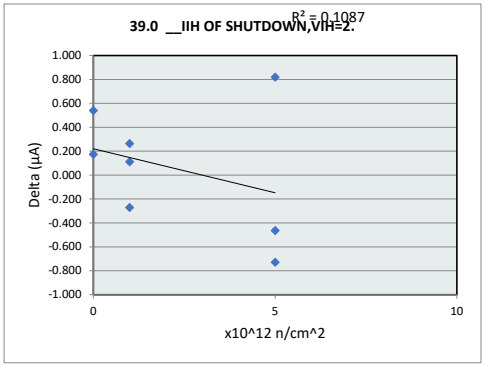
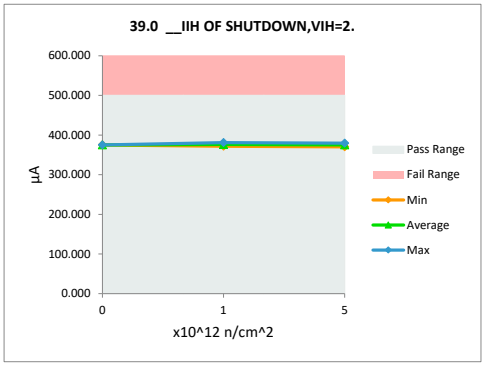
	39.0 __IIH OF SHUTDOWN,VIH=	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	500	500
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	375.895	376.157	0.263
1	113	380.841	380.951	0.110
1	114	372.134	371.862	-0.271
5	115	376.878	376.148	-0.730
5	118	380.225	379.760	-0.464
5	119	369.468	370.287	0.819
0	123	374.809	374.981	0.173
0	124	374.540	375.080	0.540
	Max	380.841	380.951	0.819
	Average	375.599	375.653	0.055
	Min	369.468	370.287	-0.730
	Std Dev	3.816	3.573	0.517



	39.0 __IIH OF SHUTDOWN,VIH		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	500	µA	
Min Limit	0	µA	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	374.981	371.862	370.287
Average	375.031	376.323	375.398
Max	375.080	380.951	379.761
UL	500.000	500.000	500.000



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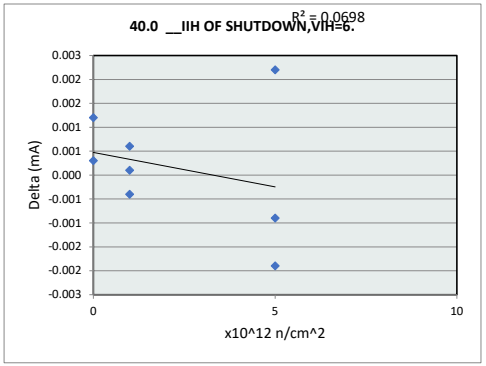
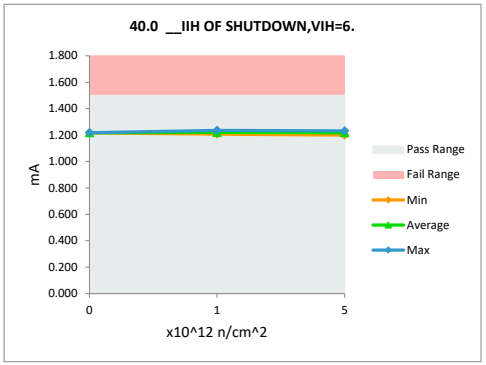
	40.0 __IIH OF SHUTDOWN,VIH=	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	1.5	1.5
Min Limit	0.005	0.005

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.220	1.220	0.000
1	113	1.235	1.236	0.001
1	114	1.207	1.207	0.000
5	115	1.221	1.219	-0.002
5	118	1.233	1.232	-0.001
5	119	1.197	1.200	0.002
0	123	1.217	1.218	0.001
0	124	1.216	1.217	0.000
	Max	1.235	1.236	0.002
	Average	1.218	1.218	0.000
	Min	1.197	1.200	-0.002
	Std Dev	0.012	0.012	0.001



	40.0 __IIH OF SHUTDOWN,VIH		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	1.5	mA	
Min Limit	0.005	mA	
x10^12 n/cm^2	0	1	5
LL	0.005	0.005	0.005
Min	1.217	1.207	1.200
Average	1.217	1.221	1.217
Max	1.218	1.236	1.232
UL	1.500	1.500	1.500



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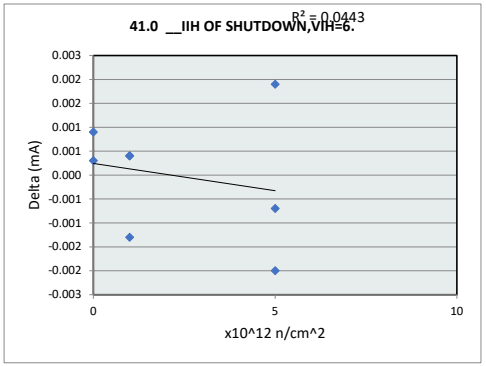
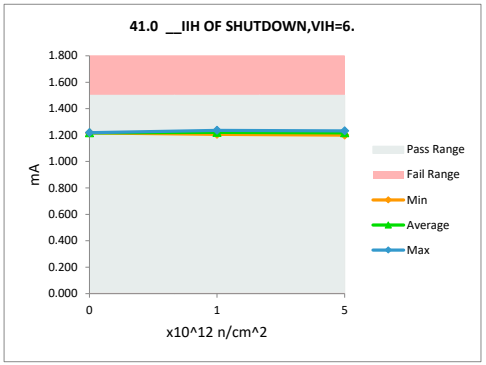
		41.0 __IIH OF SHUTDOWN,VIH=	
Test Site		MTT	MTT
Tester		LTX	LTX
Test Number		XPM02903	XPM02903
Unit		mA	mA
Max Limit		1.5	1.5
Min Limit		0.005	0.005
x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.219	1.220	0.000
1	113	1.235	1.235	0.000
1	114	1.207	1.206	-0.001
5	115	1.221	1.219	-0.002
5	118	1.233	1.232	-0.001
5	119	1.198	1.199	0.002
0	123	1.217	1.218	0.001
0	124	1.216	1.216	0.000
	Max	1.235	1.235	0.002
	Average	1.218	1.218	0.000
	Min	1.198	1.199	-0.002
	Std Dev	0.012	0.012	0.001



	41.0 __IIH OF SHUTDOWN,VIH		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	1.5	mA	
Min Limit	0.005	mA	
x10^12 n/cm^2	0	1	5
LL	0.005	0.005	0.005
Min	1.216	1.206	1.200
Average	1.217	1.220	1.217
Max	1.218	1.235	1.232
UL	1.500	1.500	1.500



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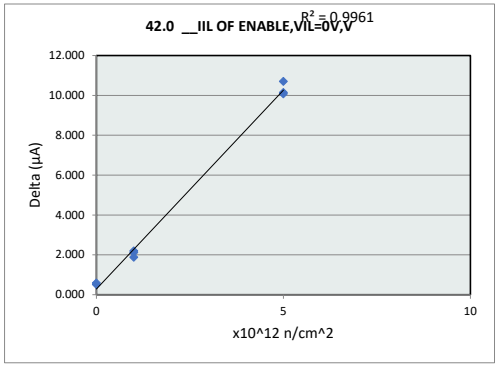
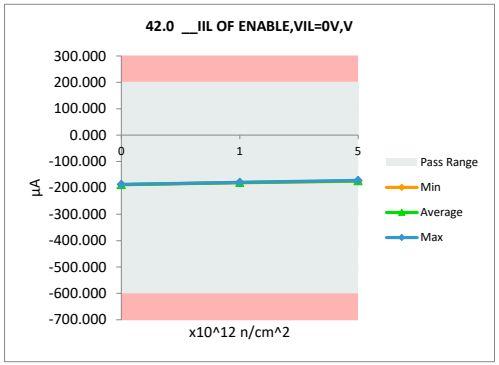
	42.0 __IIL OF ENABLE,VIL=0V,V	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	200	200
Min Limit	-600	-600

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	-181.319	-179.200	2.119
1	113	-182.597	-180.724	1.873
1	114	-181.863	-179.671	2.192
5	115	-184.798	-174.097	10.701
5	118	-181.825	-171.687	10.138
5	119	-184.722	-174.644	10.078
0	123	-187.582	-187.070	0.512
0	124	-188.616	-188.031	0.585
	Max	-181.319	-171.687	10.701
	Average	-184.165	-179.391	4.775
	Min	-188.616	-188.031	0.512
	Std Dev	2.765	5.921	4.627



	42.0 __IIL OF ENABLE,VIL=0V		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	200	µA	
Min Limit	-600	µA	
x10^12 n/cm^2	0	1	5
LL	-600.000	-600.000	-600.000
Min	-188.031	-180.724	-174.644
Average	-187.551	-179.865	-173.476
Max	-187.070	-179.200	-171.687
UL	200.000	200.000	200.000



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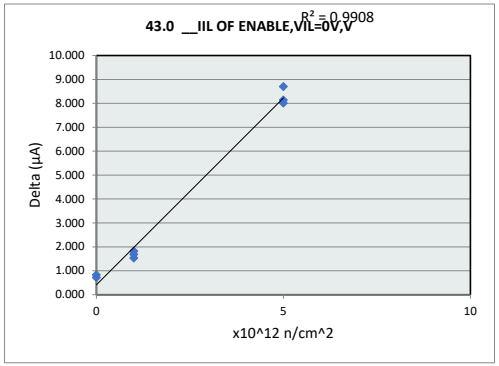
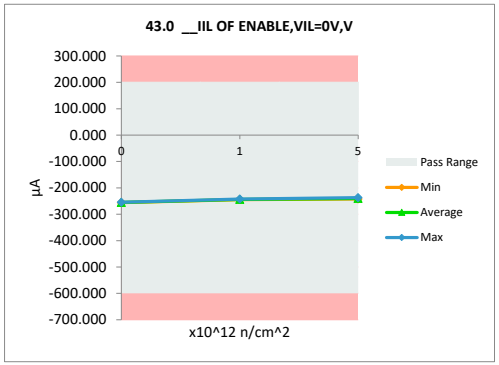
	43.0 __IIL OF ENABLE,VIL=0V,V	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	200	200
Min Limit	-600	-600

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	-244.314	-242.497	1.817
1	113	-246.194	-244.662	1.532
1	114	-245.067	-243.383	1.684
5	115	-250.748	-242.045	8.703
5	118	-245.067	-237.056	8.011
5	119	-250.014	-241.875	8.139
0	123	-255.263	-254.547	0.716
0	124	-256.729	-255.901	0.828
	Max	-244.314	-237.056	8.703
	Average	-249.175	-245.246	3.929
	Min	-256.729	-255.901	0.716
	Std Dev	4.834	6.548	3.632



	43.0 __IIL OF ENABLE,VIL=0V		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	200	µA	
Min Limit	-600	µA	
x10^12 n/cm^2	0	1	5
LL	-600.000	-600.000	-600.000
Min	-255.901	-244.662	-242.045
Average	-255.224	-243.514	-240.325
Max	-254.547	-242.497	-237.056
UL	200.000	200.000	200.000



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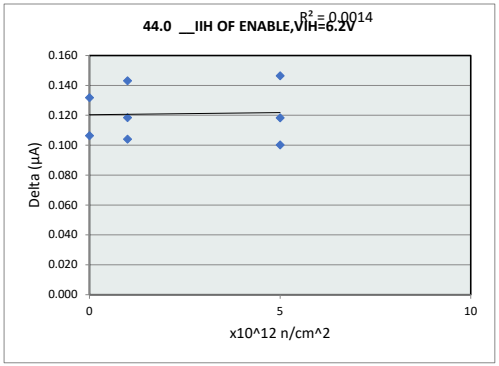
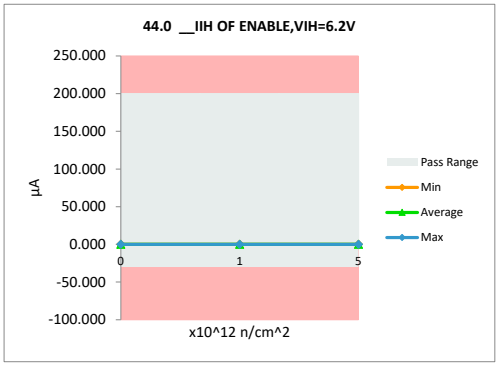
	44.0 __IIH OF ENABLE,VIH=6.2V	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	200	200
Min Limit	-30	-30

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	-0.064	0.054	0.118
1	113	-0.067	0.076	0.143
1	114	-0.062	0.043	0.104
5	115	-0.064	0.054	0.118
5	118	-0.082	0.064	0.146
5	119	-0.058	0.042	0.100
0	123	-0.062	0.044	0.106
0	124	-0.068	0.063	0.132
	Max	-0.058	0.076	0.146
	Average	-0.066	0.055	0.121
	Min	-0.082	0.042	0.100
	Std Dev	0.007	0.012	0.018



	44.0 __IIH OF ENABLE,VIH=6.		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	200	µA	
Min Limit	-30	µA	
x10^12 n/cm^2	0	1	5
LL	-30.000	-30.000	-30.000
Min	0.044	0.043	0.042
Average	0.054	0.058	0.054
Max	0.063	0.076	0.064
UL	200.000	200.000	200.000



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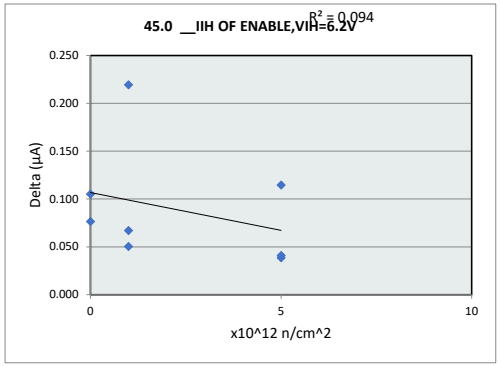
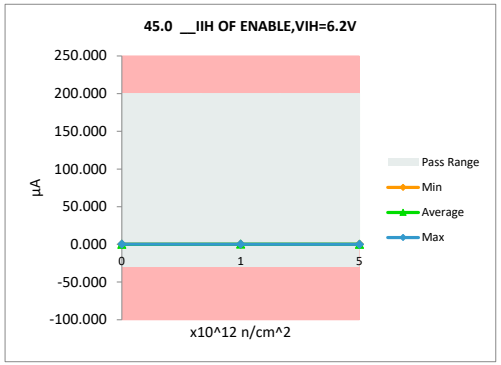
	45.0 __IIH OF ENABLE,VIH=6.2V	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	µA	µA
Max Limit	200	200
Min Limit	-30	-30

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	0.081	0.131	0.050
1	113	0.122	0.189	0.067
1	114	0.007	0.227	0.219
5	115	0.117	0.157	0.041
5	118	0.052	0.167	0.115
5	119	0.074	0.112	0.038
0	123	0.081	0.186	0.105
0	124	0.074	0.150	0.076
	Max	0.122	0.227	0.219
	Average	0.076	0.165	0.089
	Min	0.007	0.112	0.038
	Std Dev	0.036	0.036	0.060



	45.0 __IIH OF ENABLE,VIH=6.		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	200	µA	
Min Limit	-30	µA	
x10^12 n/cm^2	0	1	5
LL	-30.000	-30.000	-30.000
Min	0.150	0.131	0.112
Average	0.168	0.182	0.146
Max	0.186	0.227	0.167
UL	200.000	200.000	200.000



NDD Report
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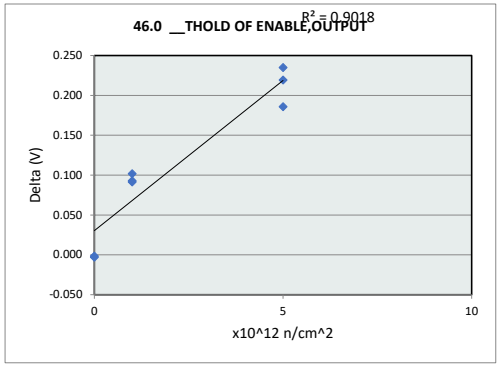
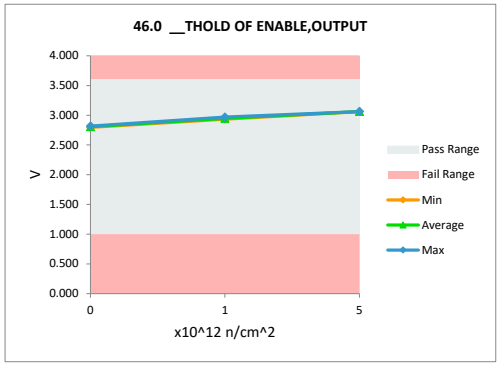
	46.0 __THOLD OF ENABLE,OUTP	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	3.6	3.6
Min Limit	1	1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	2.835	2.937	0.102
1	113	2.877	2.970	0.093
1	114	2.842	2.934	0.091
5	115	2.876	3.062	0.186
5	118	2.842	3.062	0.219
5	119	2.827	3.062	0.235
0	123	2.820	2.817	-0.003
0	124	2.798	2.796	-0.002
	Max	2.877	3.062	0.235
	Average	2.840	2.955	0.115
	Min	2.798	2.796	-0.003
	Std Dev	0.027	0.106	0.092



	46.0 __THOLD OF ENABLE,OUT		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	3.6	V	
Min Limit	1	V	
x10^12 n/cm^2	0	1	5
LL	1.000	1.000	1.000
Min	2.796	2.934	3.062
Average	2.807	2.947	3.062
Max	2.817	2.970	3.062
UL	3.600	3.600	3.600



NDD Report
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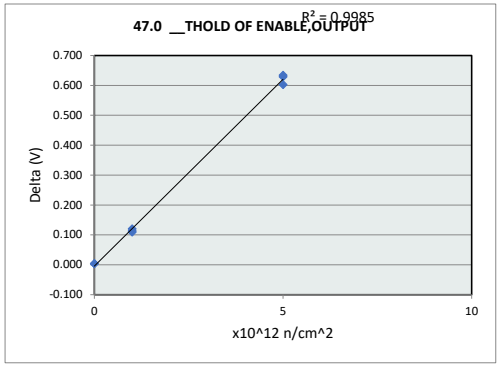
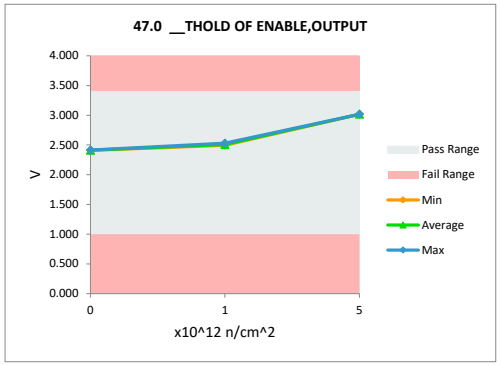
	47.0 __THOLD OF ENABLE,OUTP	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	3.4	3.4
Min Limit	1	1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	2.381	2.501	0.120
1	113	2.418	2.531	0.113
1	114	2.385	2.495	0.109
5	115	2.415	3.017	0.602
5	118	2.387	3.016	0.629
5	119	2.383	3.017	0.634
0	123	2.411	2.415	0.004
0	124	2.407	2.410	0.003
	Max	2.418	3.017	0.634
	Average	2.398	2.675	0.277
	Min	2.381	2.410	0.003
	Std Dev	0.016	0.286	0.289



	47.0 __THOLD OF ENABLE,OUT		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	3.4	V	
Min Limit	1	V	
x10^12 n/cm^2	0	1	5
LL	1.000	1.000	1.000
Min	2.410	2.495	3.016
Average	2.412	2.509	3.017
Max	2.415	2.531	3.017
UL	3.400	3.400	3.400



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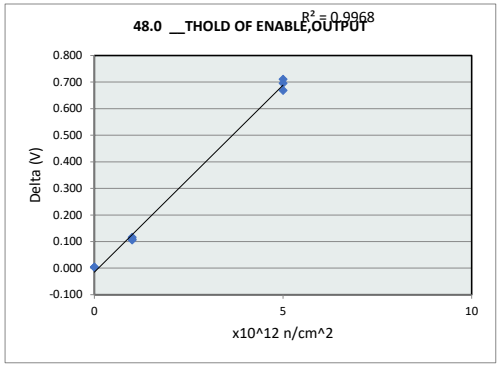
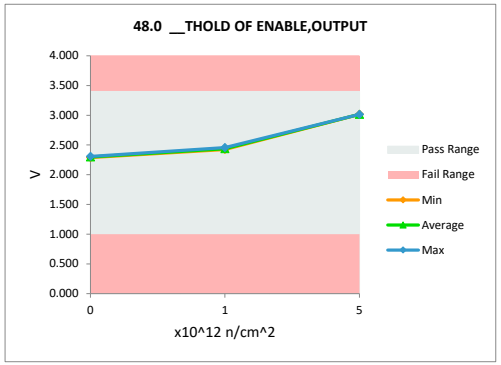
	48.0 __THOLD OF ENABLE,OUTP	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	3.4	3.4
Min Limit	1	1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	2.313	2.428	0.116
1	113	2.349	2.458	0.109
1	114	2.318	2.424	0.106
5	115	2.346	3.015	0.669
5	118	2.320	3.015	0.695
5	119	2.305	3.016	0.711
0	123	2.304	2.307	0.003
0	124	2.284	2.288	0.004
	Max	2.349	3.016	0.711
	Average	2.318	2.619	0.301
	Min	2.284	2.288	0.003
	Std Dev	0.022	0.333	0.326



	48.0 __THOLD OF ENABLE,OUT		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	3.4	V	
Min Limit	1	V	
x10^12 n/cm^2	0	1	5
LL	1.000	1.000	1.000
Min	2.288	2.424	3.015
Average	2.298	2.437	3.015
Max	2.307	2.458	3.016
UL	3.400	3.400	3.400



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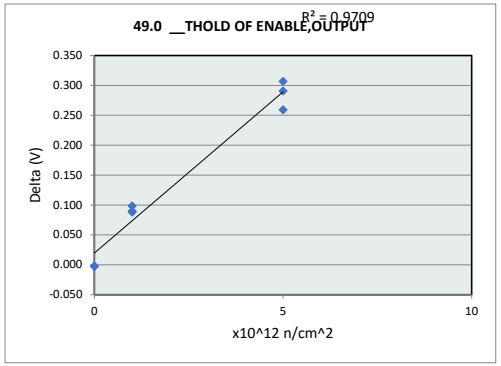
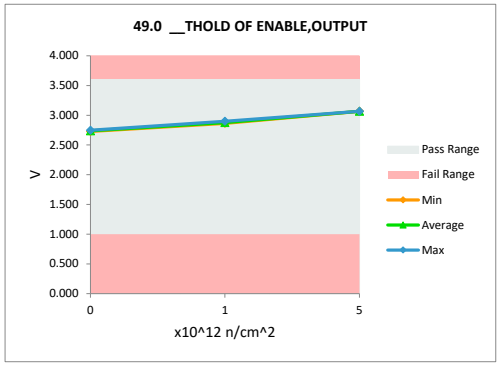
	49.0 __THOLD OF ENABLE,OUTP	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	V	V
Max Limit	3.6	3.6
Min Limit	1	1

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	2.768	2.866	0.098
1	113	2.809	2.898	0.090
1	114	2.775	2.863	0.088
5	115	2.807	3.066	0.259
5	118	2.776	3.066	0.291
5	119	2.760	3.067	0.307
0	123	2.750	2.748	-0.002
0	124	2.731	2.728	-0.003
	Max	2.809	3.067	0.307
	Average	2.772	2.913	0.141
	Min	2.731	2.728	-0.003
	Std Dev	0.027	0.140	0.127



	49.0 __THOLD OF ENABLE,OUT		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	3.6	V	
Min Limit	1	V	
x10^12 n/cm^2	0	1	5
LL	1.000	1.000	1.000
Min	2.728	2.863	3.066
Average	2.738	2.876	3.066
Max	2.748	2.898	3.067
UL	3.600	3.600	3.600



NDD Report
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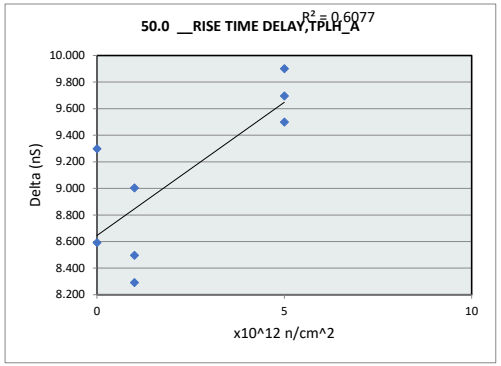
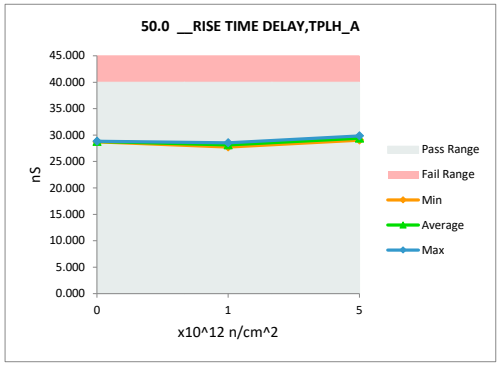
	50.0 __RISE TIME DELAY,TPLH_A	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	40	40
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	18.729	27.732	9.003
1	113	20.244	28.534	8.290
1	114	19.638	28.133	8.495
5	115	20.143	29.837	9.694
5	118	19.436	29.336	9.900
5	119	19.537	29.035	9.498
0	123	20.143	28.735	8.592
0	124	19.537	28.835	9.298
	Max	20.244	29.837	9.900
	Average	19.676	28.772	9.096
	Min	18.729	27.732	8.290
	Std Dev	0.500	0.663	0.595



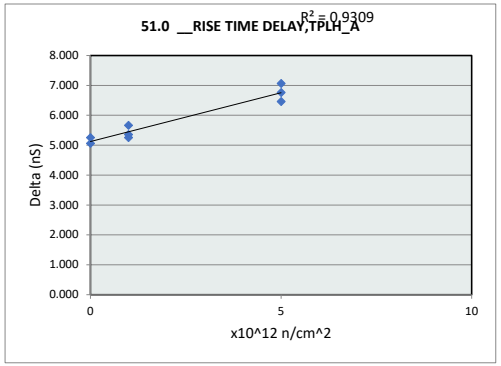
	50.0 __RISE TIME DELAY,TPLH		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	40	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	28.735	27.732	29.036
Average	28.785	28.133	29.403
Max	28.835	28.534	29.837
UL	40.000	40.000	40.000



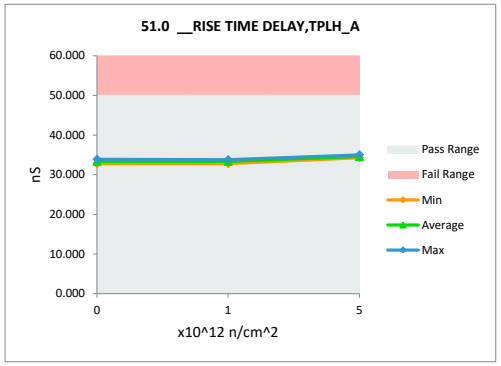
NDD Report
UC1708-SP

	51.0 __RISE TIME DELAY,TPLH_A	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	50	50
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	27.121	32.785	5.664
1	113	28.535	33.787	5.252
1	114	28.131	33.486	5.355
5	115	28.232	34.990	6.758
5	118	27.525	34.589	7.064
5	119	27.828	34.288	6.460
0	123	28.636	33.887	5.252
0	124	27.727	32.785	5.058
	Max	28.636	34.990	7.064
	Average	27.967	33.825	5.858
	Min	27.121	32.785	5.058
	Std Dev	0.515	0.796	0.783



	51.0 __RISE TIME DELAY,TPLH		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	50	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	32.785	32.785	34.288
Average	33.336	33.353	34.622
Max	33.887	33.787	34.990
UL	50.000	50.000	50.000



NDD Report
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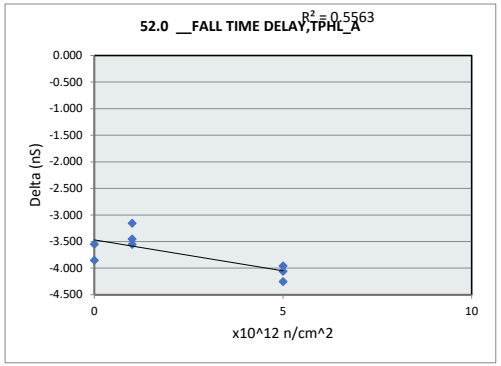
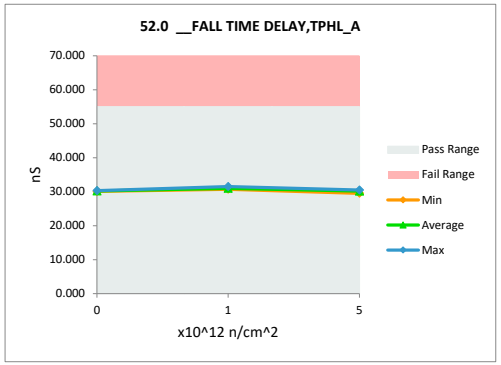
	52.0 __FALL TIME DELAY,TPHL_A	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	55	55
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	34.166	30.712	-3.455
1	113	34.671	31.514	-3.158
1	114	34.267	30.712	-3.556
5	115	34.570	30.511	-4.059
5	118	34.469	30.511	-3.958
5	119	33.762	29.509	-4.253
0	123	33.863	30.311	-3.552
0	124	33.964	30.110	-3.854
	Max	34.671	31.514	-3.158
	Average	34.217	30.486	-3.731
	Min	33.762	29.509	-4.253
	Std Dev	0.337	0.571	0.362



	52.0 __FALL TIME DELAY,TPHL		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	55	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	30.110	30.712	29.509
Average	30.211	30.979	30.177
Max	30.311	31.514	30.511
UL	55.000	55.000	55.000



NDD Report
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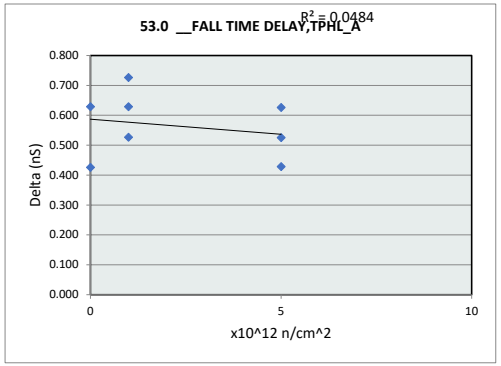
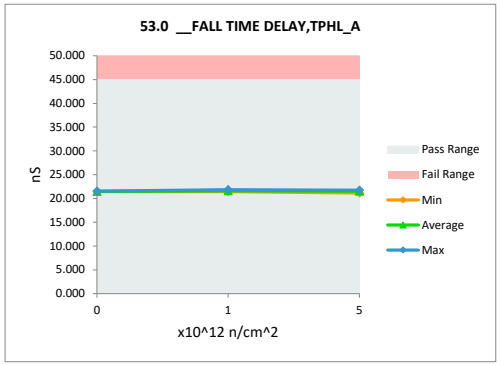
	53.0 __FALL TIME DELAY,TPHL_A	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	45	45
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	21.021	21.548	0.527
1	113	21.122	21.849	0.726
1	114	20.819	21.448	0.628
5	115	21.223	21.749	0.525
5	118	21.122	21.749	0.626
5	119	20.719	21.147	0.428
0	123	20.819	21.448	0.628
0	124	21.122	21.548	0.426
	Max	21.223	21.849	0.726
	Average	20.996	21.561	0.564
	Min	20.719	21.147	0.426
	Std Dev	0.185	0.224	0.106



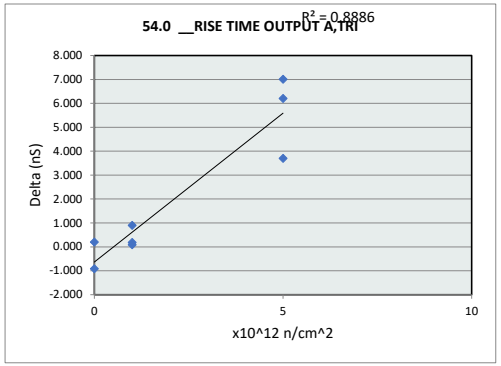
	53.0 __FALL TIME DELAY,TPHL		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	45	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	21.448	21.448	21.147
Average	21.498	21.615	21.548
Max	21.548	21.849	21.749
UL	45.000	45.000	45.000



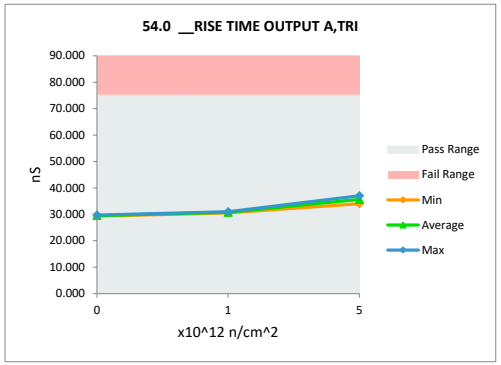
NDD Report
UC1708-SP

	54.0 __RISE TIME OUTPUT A,TRI	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	75	75
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	29.635	30.528	0.892
1	113	30.847	31.029	0.182
1	114	30.746	30.828	0.082
5	115	30.039	37.043	7.004
5	118	29.736	35.941	6.204
5	119	30.342	34.036	3.694
0	123	30.645	29.726	-0.919
0	124	29.131	29.325	0.194
	Max	30.847	37.043	7.004
	Average	30.140	32.307	2.167
	Min	29.131	29.325	-0.919
	Std Dev	0.611	2.956	3.056



	54.0 __RISE TIME OUTPUT A,T		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	75	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	29.325	30.528	34.036
Average	29.525	30.795	35.673
Max	29.726	31.029	37.043
UL	75.000	75.000	75.000



NDD Report
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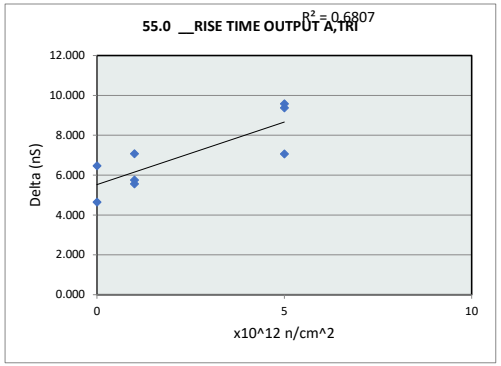
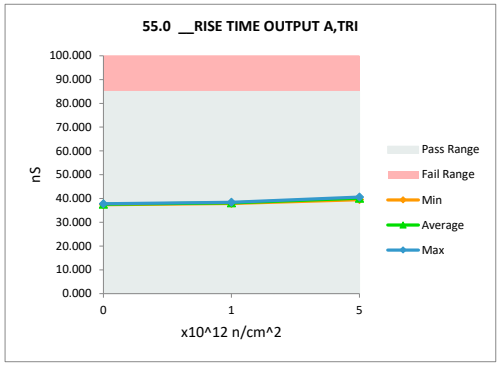
	55.0 __RISE TIME OUTPUT A,TRI	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	85	85
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	30.819	37.888	7.068
1	113	32.637	38.389	5.752
1	114	32.536	38.088	5.552
5	115	31.223	40.594	9.371
5	118	30.718	40.293	9.575
5	119	32.435	39.491	7.057
0	123	33.142	37.787	4.646
0	124	30.920	37.386	6.466
	Max	33.142	40.594	9.575
	Average	31.804	38.740	6.936
	Min	30.718	37.386	4.646
	Std Dev	0.977	1.221	1.761



	55.0 __RISE TIME OUTPUT A,T		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	85	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	37.386	37.888	39.491
Average	37.587	38.122	40.126
Max	37.787	38.389	40.594
UL	85.000	85.000	85.000



NDD Report
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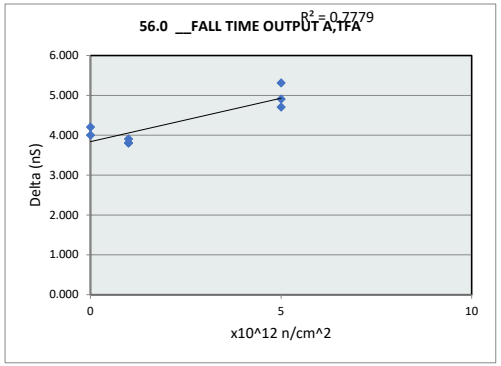
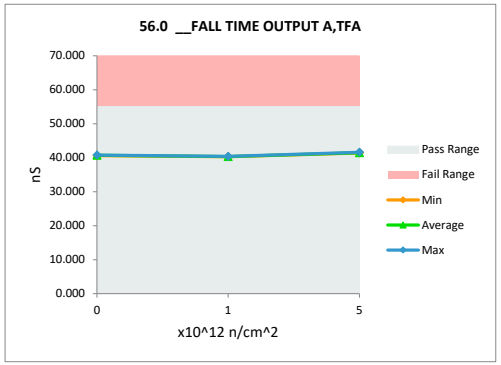
	56.0 __FALL TIME OUTPUT A,TFA	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	55	55
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	36.394	40.298	3.905
1	113	36.596	40.399	3.803
1	114	36.495	40.298	3.804
5	115	36.697	41.602	4.905
5	118	36.697	41.401	4.704
5	119	36.091	41.401	5.310
0	123	36.596	40.800	4.204
0	124	36.596	40.599	4.003
	Max	36.697	41.602	5.310
	Average	36.520	40.850	4.330
	Min	36.091	40.298	3.803
	Std Dev	0.200	0.541	0.572



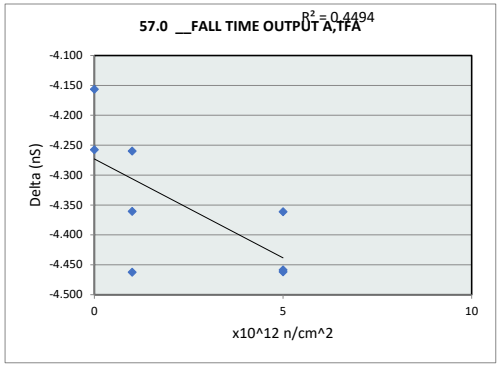
	56.0 __FALL TIME OUTPUT A,T		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	55	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	40.599	40.298	41.401
Average	40.699	40.332	41.468
Max	40.800	40.399	41.602
UL	55.000	55.000	55.000



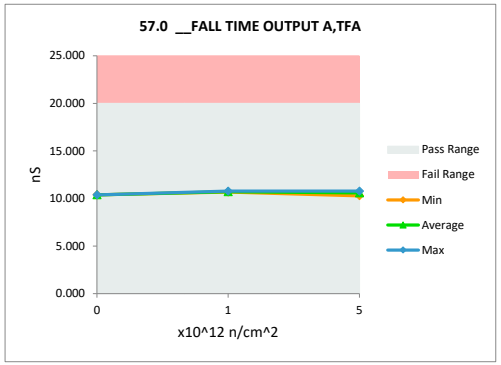
NDD Report
UC1708-SP

	57.0 __FALL TIME OUTPUT A,TFA	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	20	20
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	14.938	10.678	-4.260
1	113	15.241	10.779	-4.462
1	114	15.039	10.678	-4.361
5	115	15.140	10.678	-4.462
5	118	15.140	10.779	-4.361
5	119	14.736	10.278	-4.459
0	123	14.635	10.378	-4.258
0	124	14.534	10.378	-4.157
	Max	15.241	10.779	-4.157
	Average	14.926	10.578	-4.347
	Min	14.534	10.278	-4.462
	Std Dev	0.261	0.200	0.114



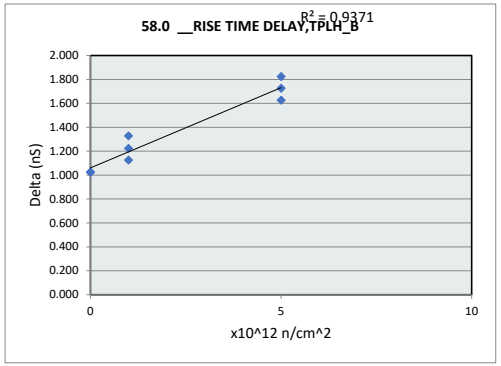
	57.0 __FALL TIME OUTPUT A,T		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	20	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	10.378	10.678	10.278
Average	10.378	10.712	10.578
Max	10.378	10.779	10.779
UL	20.000	20.000	20.000



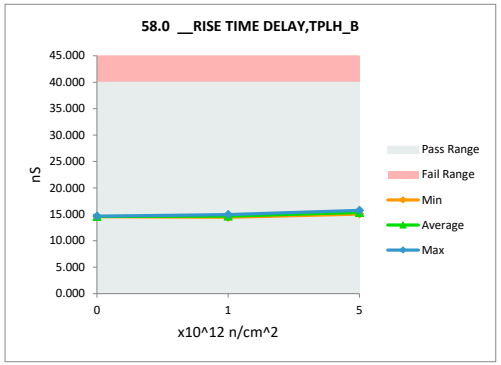
NDD Report
UC1708-SP

	58.0 __RISE TIME DELAY,TPLH_	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	40	40
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	13.223	14.550	1.327
1	113	13.728	14.951	1.223
1	114	13.324	14.450	1.126
5	115	13.930	15.753	1.823
5	118	13.526	15.252	1.726
5	119	13.425	15.052	1.626
0	123	13.627	14.651	1.023
0	124	13.526	14.550	1.024
	Max	13.930	15.753	1.823
	Average	13.539	14.901	1.362
	Min	13.223	14.450	1.023
	Std Dev	0.225	0.445	0.321



	58.0 __RISE TIME DELAY,TPLH		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	40	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	14.550	14.450	15.052
Average	14.601	14.651	15.352
Max	14.651	14.951	15.753
UL	40.000	40.000	40.000



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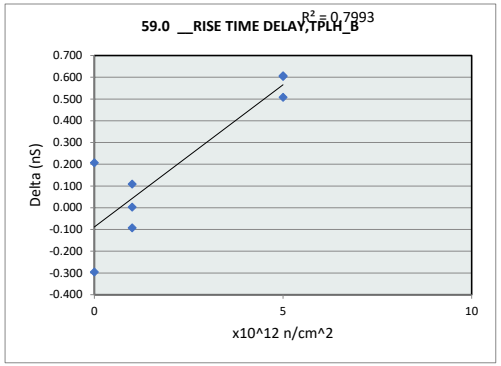
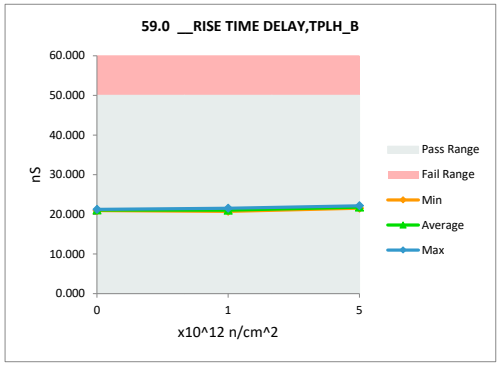
	59.0 __RISE TIME DELAY,TPLH_	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	50	50
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	20.744	20.853	0.109
1	113	21.552	21.554	0.002
1	114	20.845	20.752	-0.093
5	115	21.552	22.156	0.604
5	118	21.148	21.755	0.607
5	119	21.047	21.554	0.507
0	123	21.249	20.953	-0.296
0	124	21.047	21.253	0.207
	Max	21.552	22.156	0.607
	Average	21.148	21.354	0.206
	Min	20.744	20.752	-0.296
	Std Dev	0.296	0.488	0.338



	59.0 __RISE TIME DELAY,TPLH		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	50	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	20.953	20.752	21.554
Average	21.103	21.053	21.822
Max	21.254	21.554	22.156
UL	50.000	50.000	50.000



NDD Report
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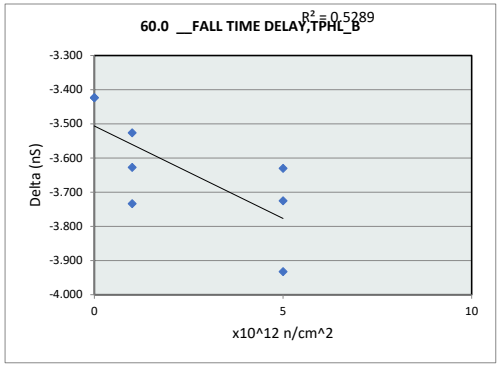
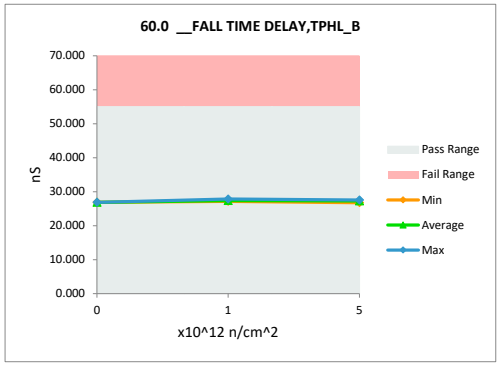
	60.0 __FALL TIME DELAY,TPHL_	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	55	55
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	30.679	27.153	-3.527
1	113	31.588	27.854	-3.734
1	114	30.780	27.153	-3.628
5	115	31.386	27.453	-3.933
5	118	31.184	27.553	-3.631
5	119	30.477	26.752	-3.726
0	123	30.275	26.852	-3.423
0	124	30.275	26.852	-3.423
	Max	31.588	27.854	-3.423
	Average	30.831	27.203	-3.628
	Min	30.275	26.752	-3.933
	Std Dev	0.503	0.390	0.172



	60.0 __FALL TIME DELAY,TPHL		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	55	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	26.852	27.153	26.752
Average	26.852	27.386	27.253
Max	26.852	27.854	27.554
UL	55.000	55.000	55.000



NDD Report
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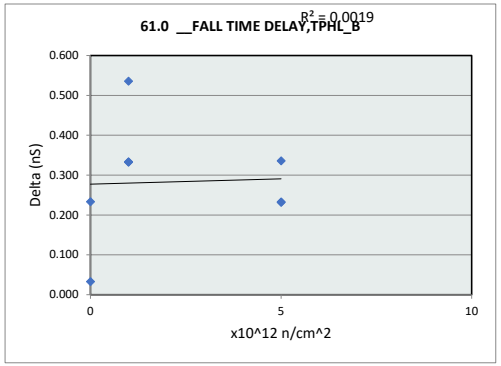
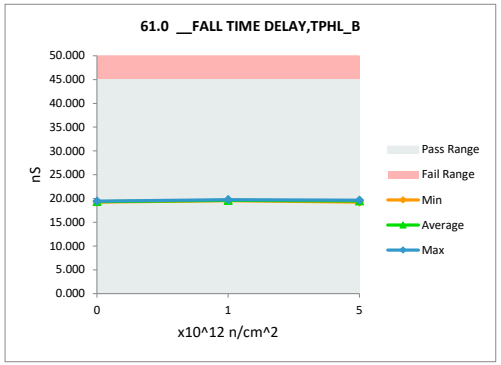
	61.0 __FALL TIME DELAY,TPHL_	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	45	45
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	19.212	19.545	0.333
1	113	19.414	19.746	0.332
1	114	19.010	19.545	0.535
5	115	19.414	19.645	0.232
5	118	19.313	19.545	0.232
5	119	18.909	19.244	0.336
0	123	19.212	19.445	0.233
0	124	19.212	19.244	0.033
	Max	19.414	19.746	0.535
	Average	19.212	19.495	0.283
	Min	18.909	19.244	0.033
	Std Dev	0.179	0.178	0.142



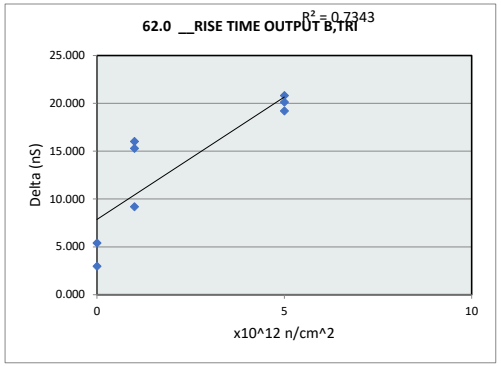
	61.0 __FALL TIME DELAY,TPHL		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	45	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	19.244	19.545	19.244
Average	19.345	19.612	19.478
Max	19.445	19.746	19.645
UL	45.000	45.000	45.000



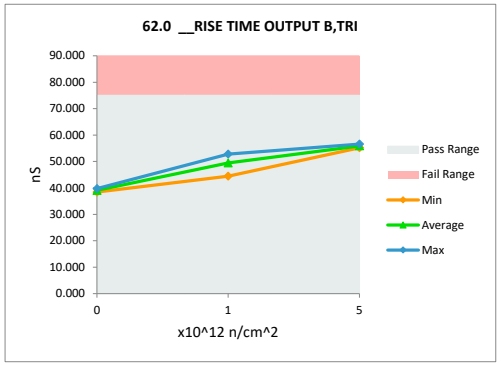
NDD Report
UC1708-SP

	62.0 __RISE TIME OUTPUT B,TRI	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	75	75
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	35.165	51.171	16.006
1	113	37.487	52.775	15.287
1	114	35.266	44.455	9.189
5	115	35.064	55.181	20.117
5	118	35.771	56.584	20.813
5	119	36.679	55.882	19.203
0	123	35.468	38.441	2.973
0	124	34.357	39.744	5.387
	Max	37.487	56.584	20.813
	Average	35.657	49.279	13.622
	Min	34.357	38.441	2.973
	Std Dev	0.991	7.361	6.911



	62.0 __RISE TIME OUTPUT B,T		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	75	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	38.441	44.455	55.181
Average	39.092	49.467	55.882
Max	39.744	52.775	56.584
UL	75.000	75.000	75.000



NDD Report
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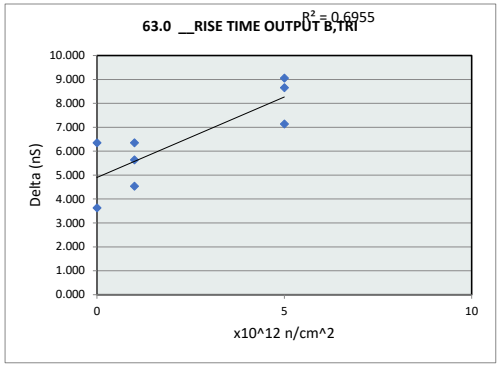
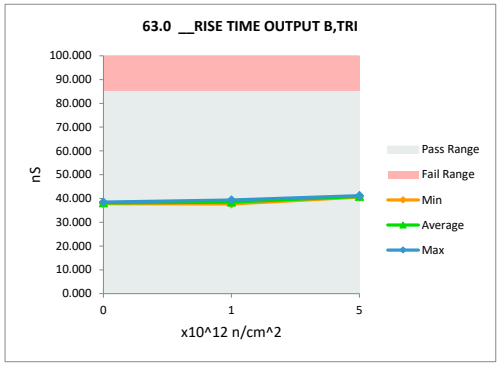
	63.0 __RISE TIME OUTPUT B,TRI	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	85	85
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	32.047	38.393	6.346
1	113	33.763	39.395	5.632
1	114	33.157	37.691	4.534
5	115	32.148	40.798	8.651
5	118	32.148	41.199	9.052
5	119	33.460	40.598	7.138
0	123	34.167	37.791	3.624
0	124	32.148	38.493	6.345
	Max	34.167	41.199	9.052
	Average	32.880	39.295	6.415
	Min	32.047	37.691	3.624
	Std Dev	0.858	1.408	1.868



	63.0 __RISE TIME OUTPUT B,T		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	85	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	37.791	37.691	40.598
Average	38.142	38.493	40.865
Max	38.493	39.395	41.199
UL	85.000	85.000	85.000



NDD Report
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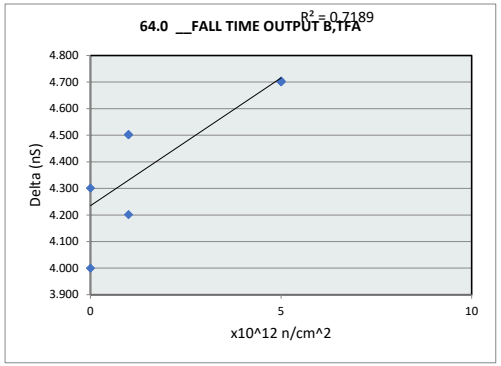
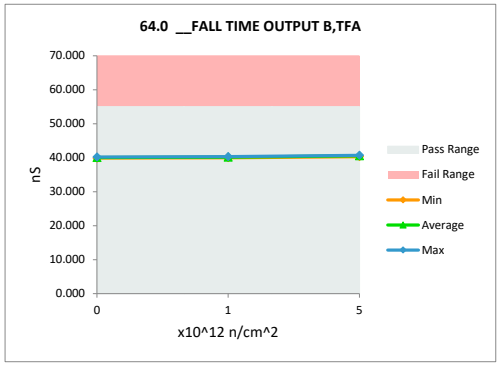
	64.0 __FALL TIME OUTPUT B,TFA	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	55	55
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	35.699	40.201	4.502
1	113	35.799	40.301	4.502
1	114	35.799	40.000	4.201
5	115	36.001	40.702	4.701
5	118	36.001	40.702	4.701
5	119	35.598	40.301	4.704
0	123	35.901	39.900	4.000
0	124	35.901	40.201	4.300
	Max	36.001	40.702	4.704
	Average	35.837	40.289	4.451
	Min	35.598	39.900	4.000
	Std Dev	0.142	0.291	0.263



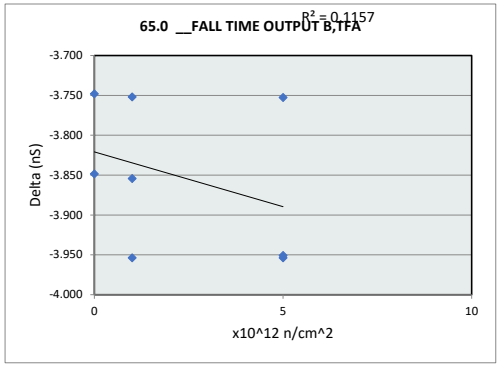
	64.0 __FALL TIME OUTPUT B,T		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	55	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	39.900	40.001	40.301
Average	40.051	40.168	40.569
Max	40.201	40.301	40.702
UL	55.000	55.000	55.000



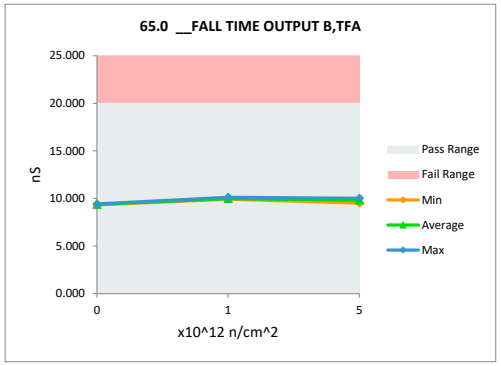
NDD Report
UC1708-SP

	65.0 __FALL TIME OUTPUT B,TFA	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	20	20
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	13.679	9.927	-3.752
1	113	13.982	10.128	-3.854
1	114	13.881	9.927	-3.954
5	115	13.881	9.927	-3.954
5	118	13.780	10.028	-3.753
5	119	13.477	9.526	-3.951
0	123	13.175	9.426	-3.748
0	124	13.175	9.326	-3.849
	Max	13.982	10.128	-3.748
	Average	13.629	9.777	-3.852
	Min	13.175	9.326	-3.954
	Std Dev	0.319	0.303	0.094



	65.0 __FALL TIME OUTPUT B,T		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	20	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	9.326	9.928	9.527
Average	9.376	9.994	9.827
Max	9.426	10.128	10.028
UL	20.000	20.000	20.000



NDD Report
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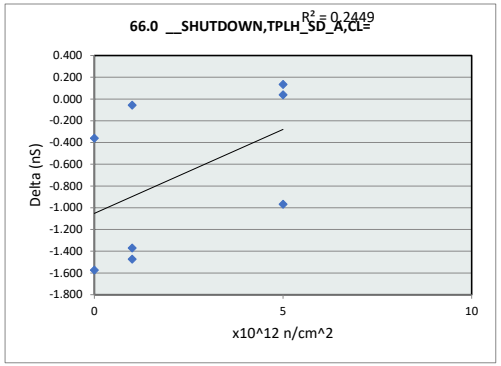
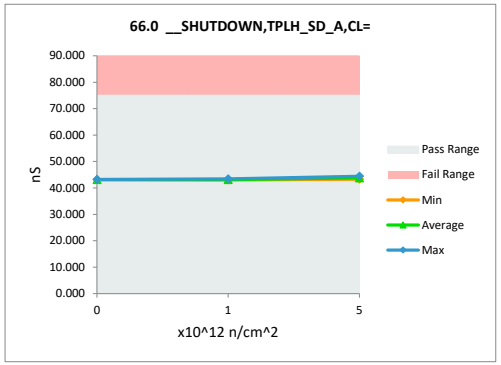
	66.0 __SHUTDOWN,TPLH_SD_A,	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	75	75
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	43.064	43.006	-0.058
1	113	44.882	43.407	-1.474
1	114	44.377	43.006	-1.371
5	115	44.276	44.410	0.134
5	118	43.670	43.708	0.038
5	119	44.276	43.307	-0.969
0	123	44.781	43.207	-1.574
0	124	43.468	43.106	-0.361
	Max	44.882	44.410	0.134
	Average	44.099	43.395	-0.704
	Min	43.064	43.006	-1.574
	Std Dev	0.640	0.472	0.722



	66.0 __SHUTDOWN,TPLH_SD_		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	75	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	43.107	43.006	43.307
Average	43.157	43.140	43.808
Max	43.207	43.407	44.410
UL	75.000	75.000	75.000



NDD Report
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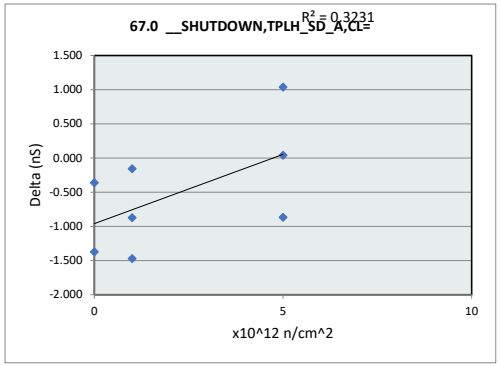
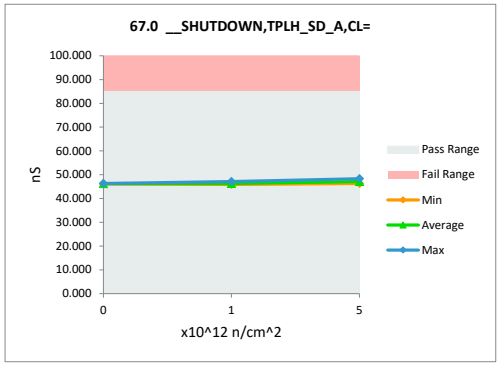
	67.0 __SHUTDOWN,TPLH_SD_A,	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	85	85
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	46.064	45.906	-0.158
1	113	47.983	47.109	-0.874
1	114	47.478	46.006	-1.472
5	115	47.276	48.312	1.036
5	118	46.670	46.708	0.038
5	119	47.175	46.307	-0.868
0	123	47.680	46.307	-1.373
0	124	46.468	46.106	-0.361
	Max	47.983	48.312	1.036
	Average	47.099	46.595	-0.504
	Min	46.064	45.906	-1.472
	Std Dev	0.649	0.797	0.825



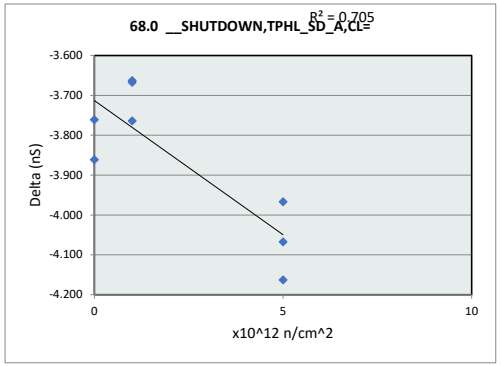
	67.0 __SHUTDOWN,TPLH_SD_		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	85	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	46.107	45.906	46.307
Average	46.207	46.340	47.109
Max	46.307	47.109	48.312
UL	85.000	85.000	85.000



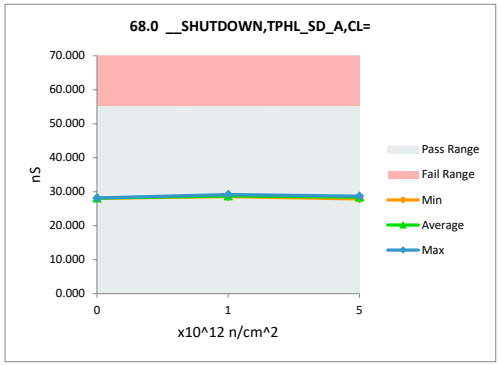
NDD Report
UC1708-SP

	68.0 __SHUTDOWN,TPHL_SD_A,	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	55	55
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	32.227	28.564	-3.663
1	113	32.833	29.165	-3.668
1	114	32.328	28.564	-3.764
5	115	32.732	28.664	-4.068
5	118	32.631	28.664	-3.967
5	119	32.025	27.862	-4.163
0	123	31.924	28.163	-3.761
0	124	31.924	28.063	-3.861
	Max	32.833	29.165	-3.663
	Average	32.328	28.464	-3.864
	Min	31.924	27.862	-4.163
	Std Dev	0.366	0.415	0.186



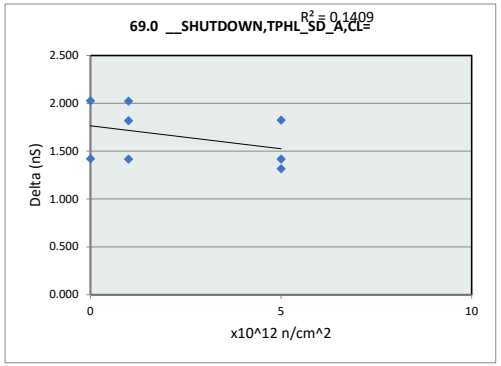
	68.0 __SHUTDOWN,TPHL_SD_		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	55	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	28.063	28.564	27.862
Average	28.113	28.764	28.397
Max	28.163	29.165	28.664
UL	55.000	55.000	55.000



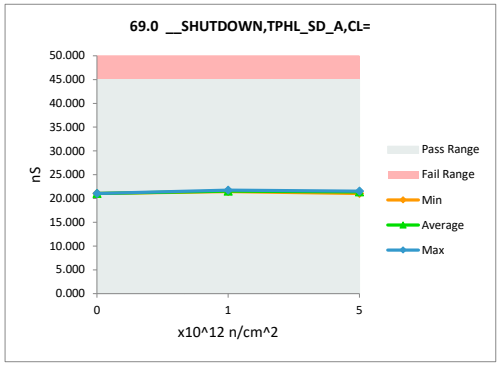
NDD Report
UC1708-SP

	69.0 __SHUTDOWN,TPHL_SD_A,	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	45	45
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	20.037	21.454	1.417
1	113	19.936	21.755	1.819
1	114	19.431	21.454	2.023
5	115	20.239	21.554	1.315
5	118	20.138	21.554	1.416
5	119	19.229	21.053	1.824
0	123	19.027	21.053	2.026
0	124	19.633	21.053	1.420
	Max	20.239	21.755	2.026
	Average	19.709	21.366	1.657
	Min	19.027	21.053	1.315
	Std Dev	0.448	0.276	0.296



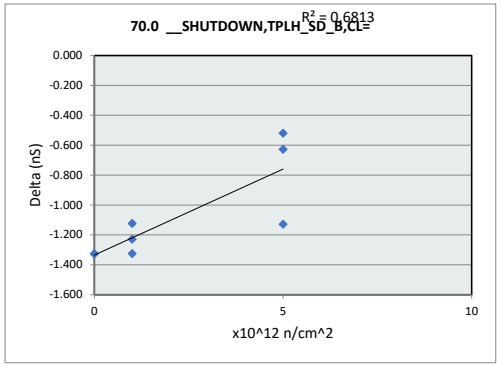
	69.0 __SHUTDOWN,TPHL_SD_		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	45	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	21.053	21.454	21.053
Average	21.053	21.554	21.387
Max	21.053	21.755	21.554
UL	45.000	45.000	45.000



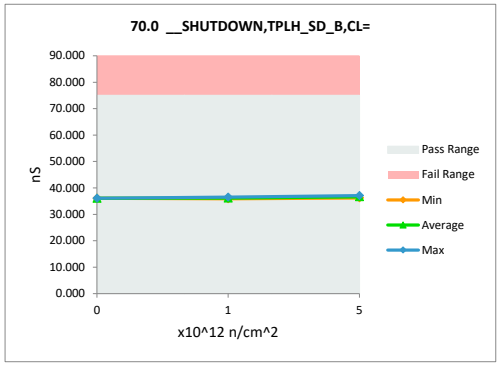
NDD Report
UC1708-SP

	70.0 __SHUTDOWN,TPLH_SD_B,	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	75	75
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	37.116	35.992	-1.124
1	113	37.722	36.493	-1.229
1	114	37.217	35.892	-1.325
5	115	37.722	37.095	-0.627
5	118	37.722	36.593	-1.129
5	119	36.712	36.192	-0.520
0	123	37.419	36.092	-1.327
0	124	37.419	36.092	-1.327
	Max	37.722	37.095	-0.520
	Average	37.381	36.305	-1.076
	Min	36.712	35.892	-1.327
	Std Dev	0.358	0.399	0.322



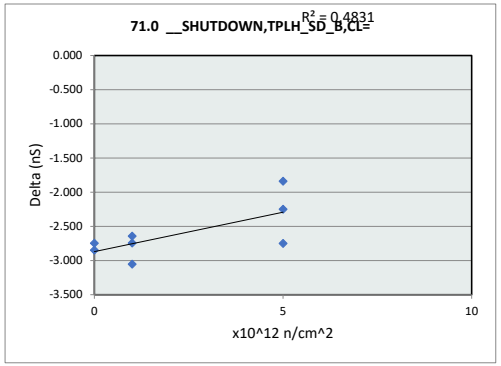
	70.0 __SHUTDOWN,TPLH_SD_		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	75	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	36.092	35.892	36.192
Average	36.092	36.126	36.627
Max	36.092	36.493	37.095
UL	75.000	75.000	75.000



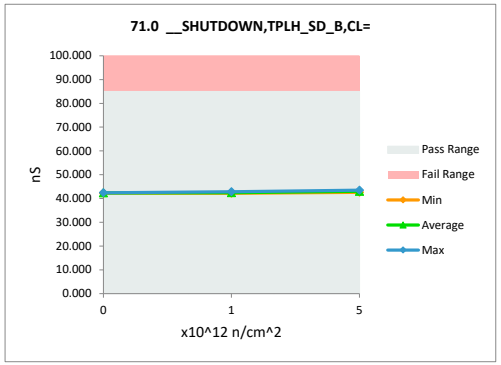
NDD Report
UC1708-SP

	71.0 __SHUTDOWN,TPLH_SD_B,	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	85	85
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	44.839	42.194	-2.645
1	113	45.848	42.795	-3.053
1	114	44.940	42.194	-2.746
5	115	45.747	43.497	-2.250
5	118	45.747	42.996	-2.752
5	119	44.435	42.595	-1.840
0	123	45.142	42.294	-2.847
0	124	45.142	42.394	-2.747
	Max	45.848	43.497	-1.840
	Average	45.230	42.620	-2.610
	Min	44.435	42.194	-3.053
	Std Dev	0.508	0.457	0.384



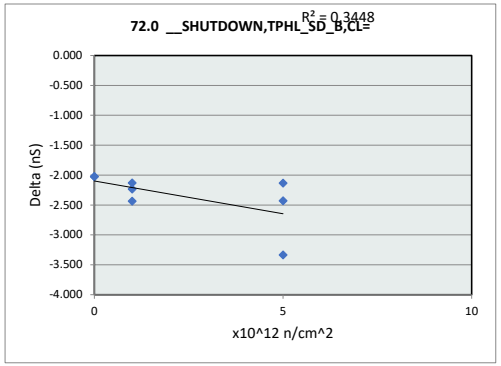
	71.0 __SHUTDOWN,TPLH_SD_		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	85	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	42.294	42.194	42.595
Average	42.344	42.394	43.029
Max	42.394	42.795	43.497
UL	85.000	85.000	85.000



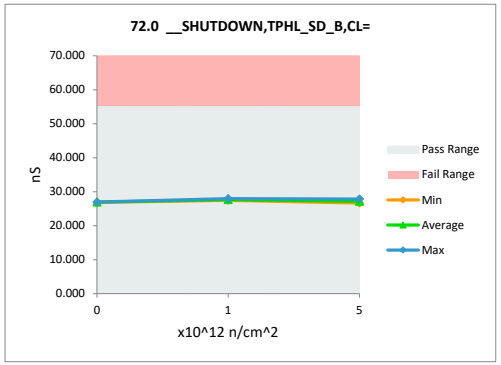
NDD Report
UC1708-SP

	72.0 __SHUTDOWN,TPHL_SD_B,	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	55	55
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	29.590	27.458	-2.131
1	113	30.398	27.960	-2.438
1	114	29.792	27.559	-2.233
5	115	29.994	26.657	-3.337
5	118	29.994	27.859	-2.135
5	119	29.388	26.957	-2.431
0	123	28.984	26.957	-2.027
0	124	28.883	26.857	-2.026
	Max	30.398	27.960	-2.026
	Average	29.628	27.283	-2.345
	Min	28.883	26.657	-3.337
	Std Dev	0.523	0.490	0.432



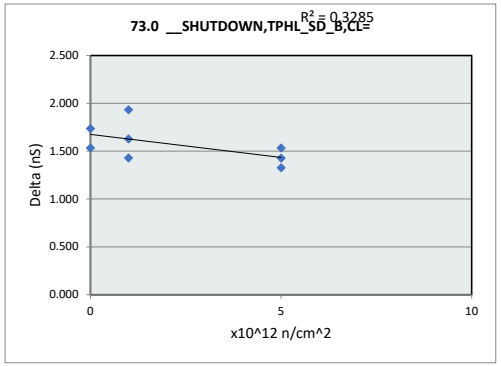
	72.0 __SHUTDOWN,TPHL_SD_		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	55	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	26.857	27.459	26.657
Average	26.907	27.659	27.158
Max	26.957	27.960	27.859
UL	55.000	55.000	55.000



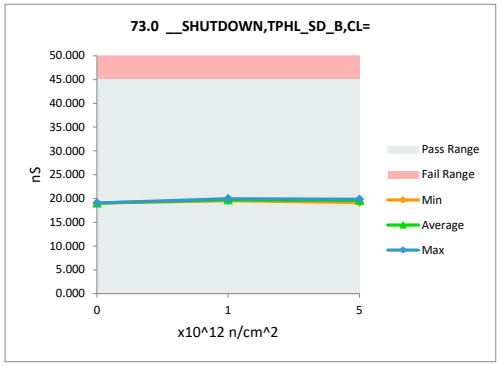
NDD Report
UC1708-SP

	73.0 __SHUTDOWN,TPHL_SD_B,	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	nS	nS
Max Limit	45	45
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	18.122	19.550	1.428
1	113	18.324	19.951	1.627
1	114	17.719	19.651	1.932
5	115	18.425	19.851	1.426
5	118	18.425	19.751	1.326
5	119	17.618	19.149	1.532
0	123	17.315	19.049	1.735
0	124	17.517	19.049	1.533
	Max	18.425	19.951	1.932
	Average	17.933	19.500	1.567
	Min	17.315	19.049	1.326
	Std Dev	0.443	0.367	0.195

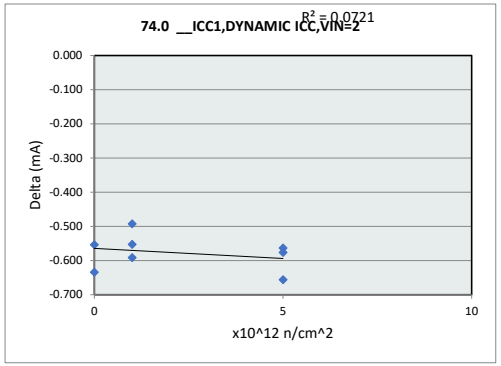


	73.0 __SHUTDOWN,TPHL_SD_		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	45	nS	
Min Limit	0	nS	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	19.049	19.550	19.149
Average	19.049	19.717	19.584
Max	19.049	19.951	19.851
UL	45.000	45.000	45.000

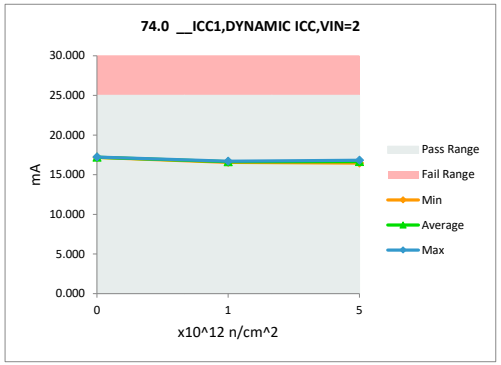


NDD Report
UC1708-SP

	74.0 __ICC1,DYNAMIC ICC,VIN=		
Test Site	MTT	MTT	
Tester	LTX	LTX	
Test Number	XPM02903	XPM02903	
Unit	mA	mA	
Max Limit	25	25	
Min Limit	0	0	
x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	17.143	16.650	-0.493
1	113	17.120	16.567	-0.553
1	114	17.293	16.702	-0.592
5	115	17.232	16.669	-0.564
5	118	17.041	16.465	-0.576
5	119	17.479	16.823	-0.656
0	123	17.819	17.185	-0.634
0	124	17.779	17.225	-0.554
	Max	17.819	17.225	-0.493
	Average	17.363	16.786	-0.578
	Min	17.041	16.465	-0.656
	Std Dev	0.299	0.279	0.051



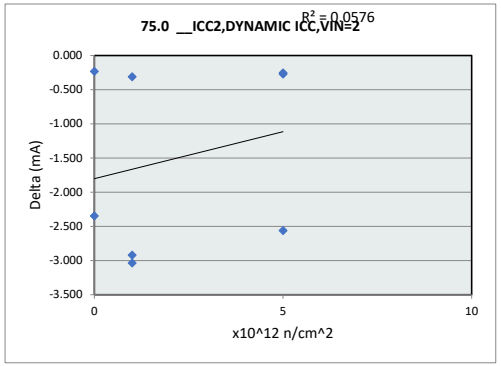
	74.0 __ICC1,DYNAMIC ICC,VIN		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	25	mA	
Min Limit	0	mA	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	17.185	16.567	16.465
Average	17.205	16.640	16.652
Max	17.225	16.702	16.823
UL	25.000	25.000	25.000



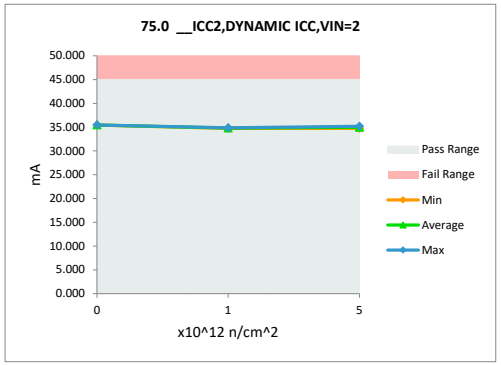
NDD Report
UC1708-SP

	75.0 __ICC2,DYNAMIC ICC,VIN=	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit	mA	mA
Max Limit	45	45
Min Limit	0	0

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	35.107	34.796	-0.311
1	113	37.662	34.740	-2.922
1	114	37.901	34.863	-3.038
5	115	35.228	34.957	-0.271
5	118	35.000	34.745	-0.256
5	119	37.749	35.187	-2.561
0	123	37.789	35.441	-2.348
0	124	35.687	35.454	-0.233
	Max	37.901	35.454	-0.233
	Average	36.515	35.023	-1.493
	Min	35.000	34.740	-3.038
	Std Dev	1.363	0.299	1.326



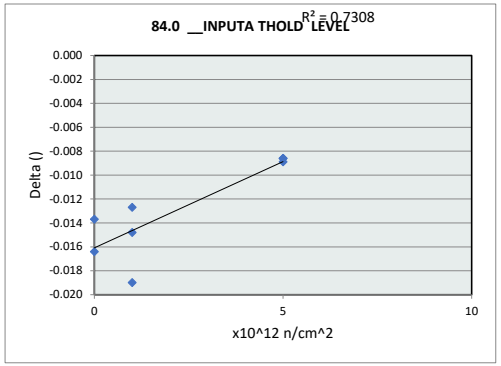
	75.0 __ICC2,DYNAMIC ICC,VIN		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	45	mA	
Min Limit	0	mA	
x10^12 n/cm^2	0	1	5
LL	0.000	0.000	0.000
Min	35.441	34.740	34.745
Average	35.447	34.800	34.963
Max	35.454	34.863	35.187
UL	45.000	45.000	45.000



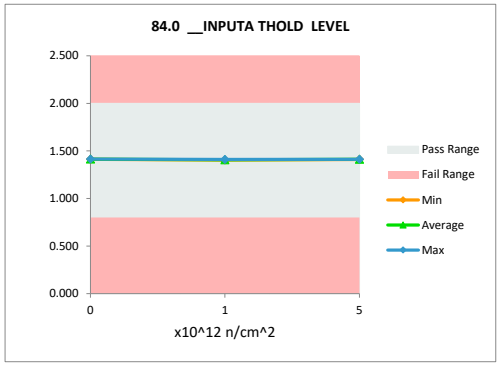
NDD Report
UC1708-SP

	84.0 __INPUTA THOLD LEVEL	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit		
Max Limit	2	2
Min Limit	0.8	0.8

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.419	1.404	-0.015
1	113	1.423	1.411	-0.013
1	114	1.425	1.406	-0.019
5	115	1.421	1.413	-0.009
5	118	1.421	1.413	-0.009
5	119	1.419	1.411	-0.009
0	123	1.428	1.412	-0.016
0	124	1.428	1.414	-0.014
	Max	1.428	1.414	-0.009
	Average	1.423	1.410	-0.013
	Min	1.419	1.404	-0.019
	Std Dev	0.004	0.004	0.004



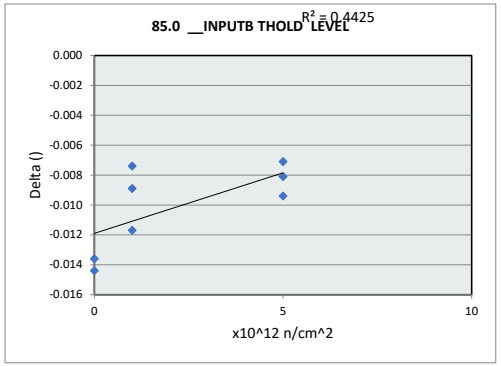
	84.0 __INPUTA THOLD LEVEL		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2		
Min Limit	0.8		
x10^12 n/cm^2	0	1	5
LL	0.800	0.800	0.800
Min	1.412	1.404	1.411
Average	1.413	1.407	1.412
Max	1.414	1.411	1.413
UL	2.000	2.000	2.000



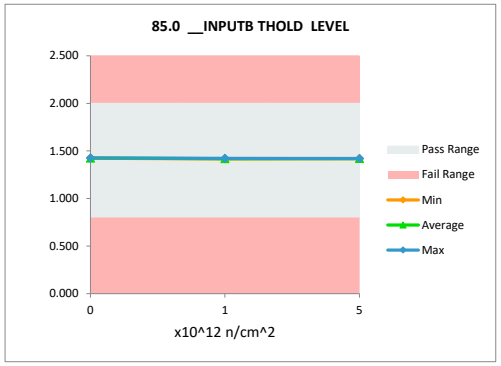
NDD Report
UC1708-SP

	85.0 __INPUTB THOLD LEVEL	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit		
Max Limit	2	2
Min Limit	0.8	0.8

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.427	1.416	-0.012
1	113	1.429	1.422	-0.007
1	114	1.427	1.418	-0.009
5	115	1.429	1.420	-0.009
5	118	1.427	1.418	-0.008
5	119	1.427	1.420	-0.007
0	123	1.438	1.423	-0.014
0	124	1.440	1.426	-0.014
	Max	1.440	1.426	-0.007
	Average	1.430	1.420	-0.010
	Min	1.427	1.416	-0.014
	Std Dev	0.005	0.003	0.003



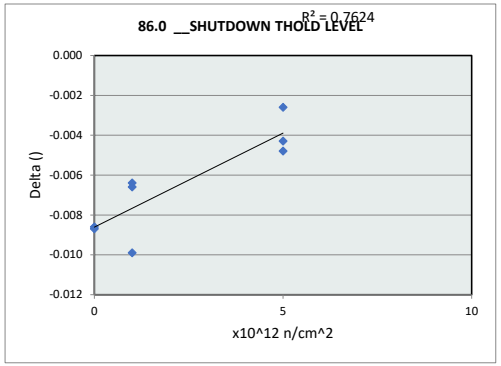
	85.0 __INPUTB THOLD LEVEL		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2		
Min Limit	0.8		
x10^12 n/cm^2	0	1	5
LL	0.800	0.800	0.800
Min	1.423	1.416	1.419
Average	1.425	1.418	1.419
Max	1.426	1.422	1.420
UL	2.000	2.000	2.000



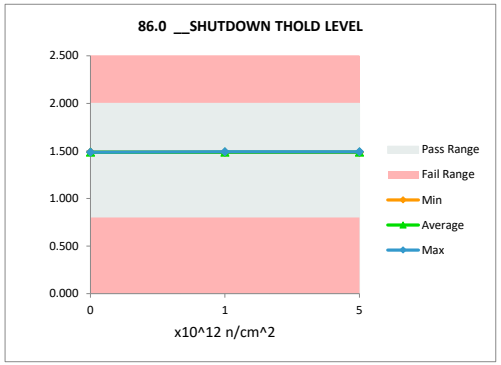
NDD Report
UC1708-SP

	86.0 __SHUTDOWN THOLD LEVE	
Test Site	MTT	MTT
Tester	LTX	LTX
Test Number	XPM02903	XPM02903
Unit		
Max Limit	2	2
Min Limit	0.8	0.8

x10^12 n/cm^2	Serial #	l708 PRE _DS_LIM	1708 POST DS LIM	Delta
1	112	1.495	1.485	-0.010
1	113	1.498	1.491	-0.007
1	114	1.491	1.485	-0.006
5	115	1.492	1.487	-0.005
5	118	1.493	1.491	-0.003
5	119	1.489	1.484	-0.004
0	123	1.495	1.486	-0.009
0	124	1.495	1.486	-0.009
	Max	1.498	1.491	-0.003
	Average	1.493	1.487	-0.006
	Min	1.489	1.484	-0.010
	Std Dev	0.003	0.003	0.003



	86.0 __SHUTDOWN THOLD LEV		
Test Site	MTT		
Tester	LTX		
Test Number	XPM02903		
Max Limit	2		
Min Limit	0.8		
x10^12 n/cm^2	0	1	5
LL	0.800	0.800	0.800
Min	1.486	1.485	1.484
Average	1.486	1.487	1.487
Max	1.486	1.491	1.491
UL	2.000	2.000	2.000



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